



# Micron Serial NOR Flash Memory

**1.8V, Multiple I/O, 4KB, 32KB, 64KB Sector Erase**

**MT25QU512AB**

## Features

- SPI-compatible serial bus interface
- Single and double transfer rate (STR/DTR)
- 1.7–2.0V single supply voltage
- Clock frequency
  - 133 MHz (MAX) for all protocols in STR
  - 66 MHz (MAX) for all protocols in DTR
- Dual/quad I/O commands for increased throughput up to 65 MB/s
- Supported protocols in both STR and DTR
  - Extended I/O protocol
  - Dual I/O protocol
  - Quad I/O protocol
- Execute-in-place (XIP)
- PROGRAM/ERASE SUSPEND operations
- Device configurable
  - Volatile and nonvolatile configuration settings
- Software reset
- Additional reset pin for selected part numbers
- 3-byte and 4-byte address modes – both enable memory access beyond 128Mb
- Dedicated 64-byte one-time programmable (OTP) area outside the main memory array
  - Readable and user-lockable
  - Permanent lock with PROGRAM OTP command
- Erase capability
  - Bulk erase
  - Sector erase 64Kb uniform granularity
  - Subsector erase 4Kb, 32Kb uniform granularity
- Security and write protection
  - Volatile and nonvolatile locking and software write protection for each 64KB sector
  - Nonvolatile configuration locking
  - Password protection
  - Hardware write protection: protected area size defined by nonvolatile bits (BP[3:0] and TB)
  - Program/erase protection during power-up
  - Cyclic redundancy check (CRC) operations detect accidental changes to raw data
- Electronic signature
  - JEDEC-standard 3-byte signature (BA20h)
  - Extended device ID: Two additional bytes to identify device factory options
- JESD47H-compliant
  - Minimum 100,000 ERASE cycles per sector
  - Data retention: 20 years (TYP)
- Packages – JEDEC-standard, RoHS-compliant
  - 16-pin SOP2, 300 mils (SO16W, SO16-Wide, SO-IC-16)
  - 24-ball T-PBGA 05/6mm x 8mm (TBGA24)

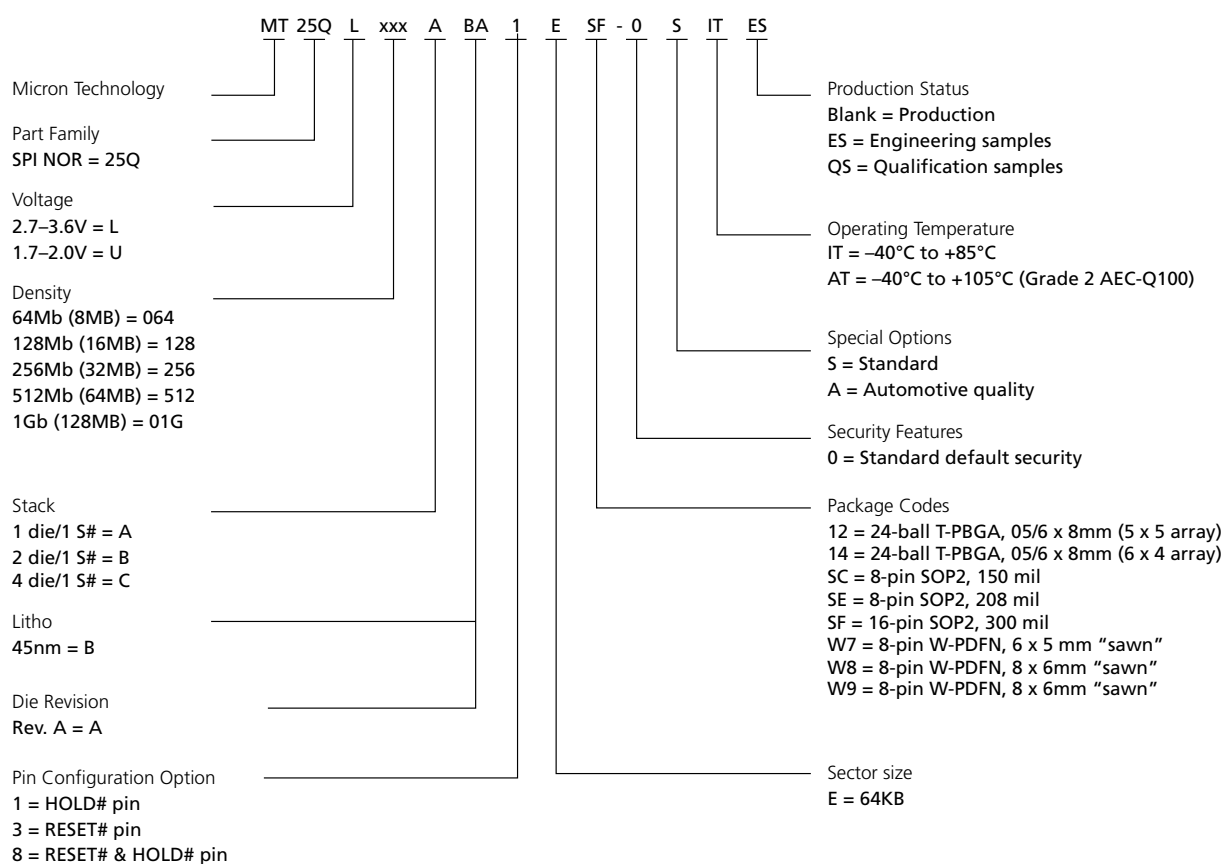


## 512Mb, 1.8V Multiple I/O Serial Flash Memory Features

### Part Number Ordering

Micron Serial NOR Flash devices are available in different configurations and densities. Verify valid part numbers by using Micron's part catalog search at [www.micron.com](http://www.micron.com). To compare features and specifications by device type, visit [www.micron.com/products](http://www.micron.com/products). Contact the factory for devices not found.

**Figure 1: Part Number Ordering Information**





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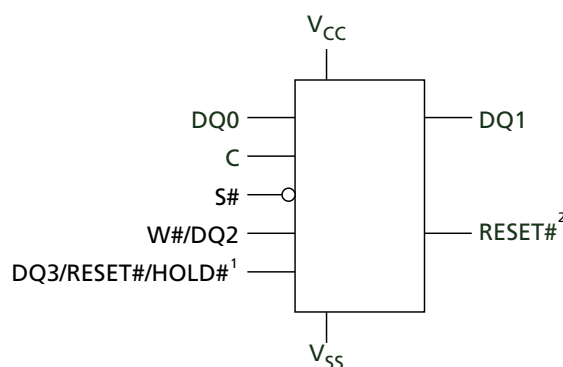
## 512Mb, 1.8V Multiple I/O Serial Flash Memory Device Description

### Device Description

The MT25Q is a high-performance multiple input/output serial Flash memory device manufactured on 45nm NOR technology. It features a high-speed SPI-compatible bus interface, execute-in-place (XIP) functionality, advanced write protection mechanisms, and extended address access. Innovative, high-performance, dual and quad input/output commands enable double or quadruple the transfer bandwidth for READ and PROGRAM operations.

### Device Diagram

Figure 2: Logic Diagram



- Notes:
1. Depending on the selected device (see Part Numbering Ordering Information), DQ3 = DQ3/RESET or DQ3/HOLD.
  2. This RESET pin is available on dedicated part numbers (see Part Numbering Ordering Information).

### Advanced Security Protection

The MT25Q offers an advanced security protection scheme where each sector can be independently locked, by either volatile or nonvolatile locking features. The nonvolatile locking configuration can also be locked, as well password-protected. See Block Protection Settings and Sector and Password Protection for more details.

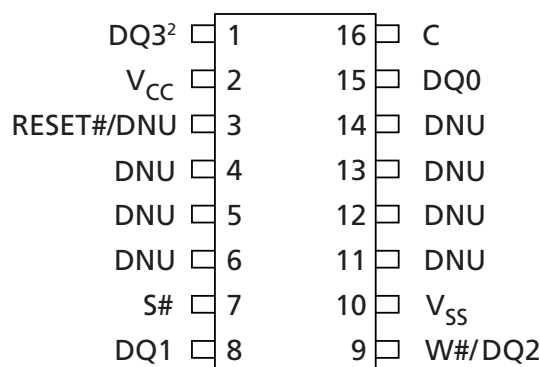




## 512Mb, 1.8V Multiple I/O Serial Flash Memory Signal Assignments

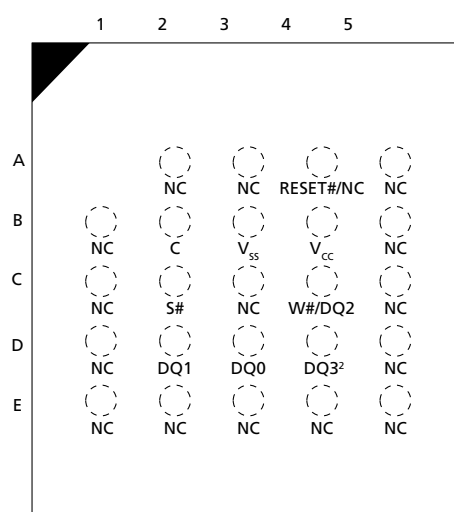
### Signal Assignments

**Figure 3: 16-Pin, Plastic Small Outline – SO16 (Top View)**



- Notes:
1. See Part Number Ordering Information for complete package names and details.
  2. Depending on the selected device (see Part Numbering Ordering Information), DQ3 = DQ3/RESET# or DQ3/HOLD#.

**Figure 4: 24-Ball TBGA (Balls Down)**



- Notes:
1. See Part Number Ordering Information for complete package names and details.
  2. Depending on the selected device (see Part Numbering Ordering Information), DQ3 = DQ3/RESET# or DQ3/HOLD#.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Signal Descriptions

### Signal Descriptions

The signal description table below is a comprehensive list of signals for the MT25Q family devices. All signals listed may not be supported on this device. See Signal Assignments for information specific to this device.

**Table 1: Signal Descriptions**

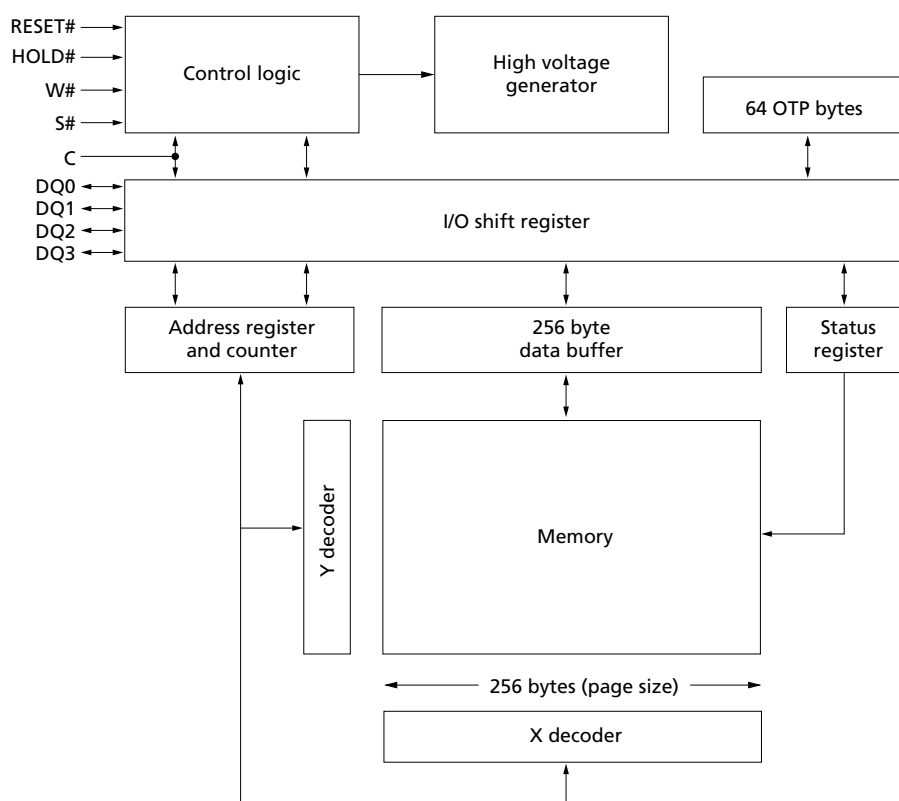
Symbol	Type	Description
S#	Input	<p><b>Chip select:</b> When S# is driven HIGH, the device will enter standby mode, unless an internal PROGRAM, ERASE, or WRITE STATUS REGISTER cycle is in progress. All other input pins are ignored and the output pins are tri-stated. On parts with the pin configuration offering a dedicated RESET# pin, however, the RESET# input pin remains active even when S# is HIGH.</p> <p>Driving S# LOW enables the device, placing it in the active mode.</p> <p>After power-up, a falling edge on S# is required prior to the start of any command.</p>
C	Input	<p><b>Clock:</b> Provides the timing of the serial interface. Command inputs are latched on the rising edge of the clock. In STR commands or protocol, address and data inputs are latched on the rising edge of the clock, while data is output on the falling edge of the clock. In DTR commands or protocol, address and data inputs are latched on both edges of the clock, and data is output on both edges of the clock.</p>
RESET#	Input	<p><b>RESET#:</b> When RESET# is driven LOW, the device is reset and the outputs are tri-stated. If RESET# is driven LOW while an internal WRITE, PROGRAM, or ERASE operation is in progress, data may be lost. The RESET# functionality can be disabled using bit 4 of the nonvolatile configuration register or bit 4 of the enhanced volatile configuration register.</p> <p>For pin configurations that share the DQ3 pin with RESET#, the RESET# functionality is disabled in QIO-SPI mode.</p>
HOLD#	Input	<p><b>HOLD:</b> Pauses serial communications with the device without deselecting or resetting the device. Outputs are tri-stated and inputs are ignored. The HOLD# functionality can be disabled using bit 4 of the nonvolatile configuration register or bit 4 of the enhanced volatile configuration register.</p> <p>HOLD# functionality is disabled in QIO-SPI mode or when DTR operation is enabled.</p>
W#	Input	<p><b>Write protect:</b> When LOW, the blocks defined by the block protection bits BP[3:0] are protected against PROGRAM or ERASE operations. Status register bit 7 should be set to 1 to enable write protection.</p>
DQ[3:0]	I/O	<p><b>Serial I/O:</b> The bidirectional DQ signals transfer address, data, and command information.</p> <p>When using legacy (x1) SPI commands in extended I/O protocol (XIO-SPI), DQ0 is an input and DQ1 is an output. DQ[3:2] are not used.</p> <p>When using dual commands in XIO-SPI or when using DIO-SPI, DQ[1:0] are I/O. DQ[3:2] are not used.</p> <p>When using quad commands in XIO-SPI or when using QIO-SPI, DQ[3:0] are I/O.</p>
V <sub>CC</sub>	Supply	Core and I/O power supply.
V <sub>SS</sub>	Supply	Core and I/O ground connection.
DNU	–	Do not use. Must be left floating.
NC	–	No connect. Not internally connected.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Memory Organization

### Memory Organization

Figure 5: Block Diagram



Note: 1. Each page of memory can be individually programmed, but the device is not page-erasable.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Memory Map – 512Mb Density

### Memory Map – 512Mb Density

Table 2: Sectors[1023:0]

Sector	32KB Subsectors	4KB Subsector	Address Range	
			Start	End
1023	2047	16383	03FF F000h	03FF FFFFh
		⋮	⋮	⋮
	2046	⋮	⋮	⋮
		16368	03FF 0000h	03FF 0FFFh
⋮		⋮	⋮	⋮
511	1023	8191	01FF F000h	01FF FFFFh
		⋮	⋮	⋮
	1022	⋮	⋮	⋮
		8176	01FF 0000h	01FF 0FFFh
⋮		⋮	⋮	⋮
255	511	4095	00FF F000h	00FF FFFFh
		⋮	⋮	⋮
	510	⋮	⋮	⋮
		4080	00FF 0000h	00FF 0FFFh
⋮		⋮	⋮	⋮
127	255	2047	007F F000h	007F FFFFh
		⋮	⋮	⋮
	254	⋮	⋮	⋮
		2032	007F 0000h	007F 0FFFh
⋮		⋮	⋮	⋮
63	125	1023	003F F000h	003F FFFFh
		⋮	⋮	⋮
	124	⋮	⋮	⋮
		1008	003F 0000h	003F 0FFFh
⋮		⋮	⋮	⋮
0	1	15	0000 F000h	0000 FFFFh
		⋮	⋮	⋮
	0	⋮	⋮	⋮
		0	0000 0000h	0000 0FFFh

Note: 1. See Part Number Ordering Information, Sector Size–Part Numbers table for options.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Status Register

### Status Register

Status register bits can be read from or written to using READ STATUS REGISTER or WRITE STATUS REGISTER commands, respectively. When the status register enable/disable bit (bit 7) is set to 1 and W# is driven LOW, the status register nonvolatile bits become read-only and the WRITE STATUS REGISTER operation will not execute. The only way to exit this hardware-protected mode is to drive W# HIGH.

**Table 3: Status Register**

Bit	Name	Settings	Description	Notes
7	Status register write enable/disable	0 = Enabled 1 = Disabled	<b>Nonvolatile control bit:</b> Used with W# to enable or disable writing to the status register.	
5	Top/bottom	0 = Top 1 = Bottom	<b>Nonvolatile control bit:</b> Determines whether the protected memory area defined by the block protect bits starts from the top or bottom of the memory array.	1
6, 4:2	BP[3:0]	See Protected Area tables	<b>Nonvolatile control bit:</b> Defines memory to be software protected against PROGRAM or ERASE operations. When one or more block protect bits is set to 1, a designated memory area is protected from PROGRAM and ERASE operations.	1
1	Write enable latch	0 = Clear (default) 1 = Set	<b>Volatile control bit:</b> The device always powers up with this bit cleared to prevent inadvertent WRITE, PROGRAM, or ERASE operations. To enable these operations, the WRITE ENABLE operation must be executed first to set this bit.	2
0	Write in progress	0 = Ready 1 = Busy	<b>Status bit:</b> Indicates if one of the following command cycles is in progress: WRITE STATUS REGISTER WRITE NONVOLATILE CONFIGURATION REGISTER PROGRAM ERASE	3

- Notes:
1. The BULK ERASE command is executed only if all bits = 0.
  2. In the case of protection error, this volatile bit is set and can be reset only with a CLEAR FLAG STATUS REGISTER command.
  3. Status register bit 0 is the inverse of flag status register bit 7.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Status Register

### Block Protection Settings

Table 4: Protected Area

Status Register Content					Protected Area
Top/Bottom	BP3	BP2	BP1	BP0	64KB Sectors
0	0	0	0	0	None
0	0	0	0	1	1023:1023
0	0	0	1	0	1023:1022
0	0	0	1	1	1023:1020
0	0	1	0	0	1023:1016
0	0	1	0	1	1023:1008
0	0	1	1	0	1023:992
0	0	1	1	1	1023:960
0	1	0	0	0	1023:896
0	1	0	0	1	1023:768
0	1	0	1	0	1023:512
0	1	0	1	1	1023:0
0	1	1	0	0	1023:0
0	1	1	0	1	1023:0
0	1	1	1	0	1023:0
0	1	1	1	1	1023:0
1	0	0	0	0	None
1	0	0	0	1	0:0
1	0	0	1	0	1:0
1	0	0	1	1	3:0
1	0	1	0	0	7:0
1	0	1	0	1	15:0
1	0	1	1	0	31:0
1	0	1	1	1	63:0
1	1	0	0	0	127:0
1	1	0	0	1	255:0
1	1	0	1	0	511:0
1	1	0	1	1	1023:0
1	1	1	0	0	1023:0
1	1	1	0	1	1023:0
1	1	1	1	0	1023:0
1	1	1	1	1	1023:0



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Flag Status Register

### Flag Status Register

Flag status register bits are read by using READ FLAG STATUS REGISTER command. All bits are volatile and are reset to zero on power up.

Status bits are set and reset automatically by the internal controller. Error bits must be cleared through the CLEAR STATUS REGISTER command.

**Table 5: Flag Status Register**

Bit	Name	Settings	Description
7	Program or erase controller	0 = Busy 1 = Ready	<b>Status bit:</b> Indicates whether one of the following command cycles is in progress: WRITE STATUS REGISTER, WRITE NONVOLATILE CONFIGURATION REGISTER, PROGRAM, or ERASE.
6	Erase suspend	0 = Clear 1 = Suspend	<b>Status bit:</b> Indicates whether an ERASE operation has been or is going to be suspended.
5	Erase	0 = Clear 1 = Failure or protection error	<b>Error bit:</b> Indicates whether an ERASE operation has succeeded or failed.
4	Program	0 = Clear 1 = Failure or protection error	<b>Error bit:</b> Indicates whether a PROGRAM operation has succeeded or failed.
3	Reserved	X = 0	
2	Program suspend	0 = Clear 1 = Suspend	<b>Status bit:</b> Indicates whether a PROGRAM operation has been or is going to be suspended.
1	Protection	0 = Clear 1 = Failure or protection error	<b>Error bit:</b> Indicates whether an ERASE or PROGRAM operation has attempted to modify the protected array sector, or whether a PROGRAM operation has attempted to access the locked OTP space.
0	Addressing	0 = 3-byte addressing 1 = 4-byte addressing	<b>Volatile control bit:</b> Indicates whether 3-byte or 4-byte address mode is enabled.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Extended Address Register

### Extended Address Register

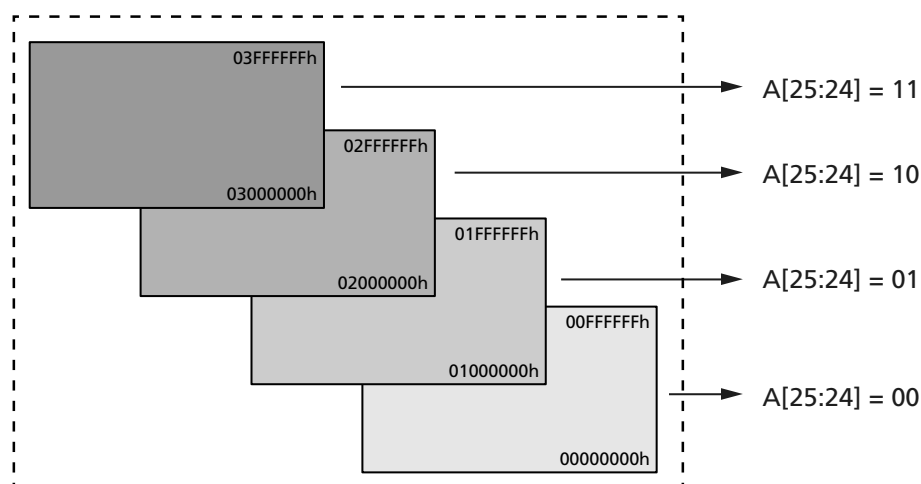
The 3-byte address mode can only access 128Mb of memory. To access the full device in 3-byte address mode, the device includes an extended address register that indirectly provides a fourth address byte A[31:24]. The extended address register bits [1:0] operate as memory address bit A[25:24] to select one of the four 128Mb segments of the memory array.

If 4-byte addressing is enabled, the extended address register settings are ignored.

**Table 6: Extended Address Register**

Bit	Name	Settings	Description
7:2	A[31:26]	000000	Reserved
1:0	A[25:24]	11 = Upper 128Mb segment 10 = Third 128Mb segment 01 = Second 128Mb segment 00 = Lower 128Mb segment (default)	Enables specified 128Mb memory segment. The default setting can be changed to the upper 128Mb segment using bit 1 of the nonvolatile configuration register.

**Figure 6: Upper and Lower Memory Array Segments**



The PROGRAM and ERASE operations act upon the 128Mb segment selected in the extended address register. The BULK ERASE operation erases the entire device.

The READ operation begins reading in the selected 128Mb segment, but is not bound by it.

In a continuous READ, when the last byte of the segment is read, the next byte output is the first byte of the next segment. The operation wraps to 0000000h; therefore, a download of the whole array is possible with one READ operation.

The value of the extended address register does not change when a READ operation crosses the selected 128Mb boundary.





## 512Mb, 1.8V Multiple I/O Serial Flash Memory Internal Configuration Register

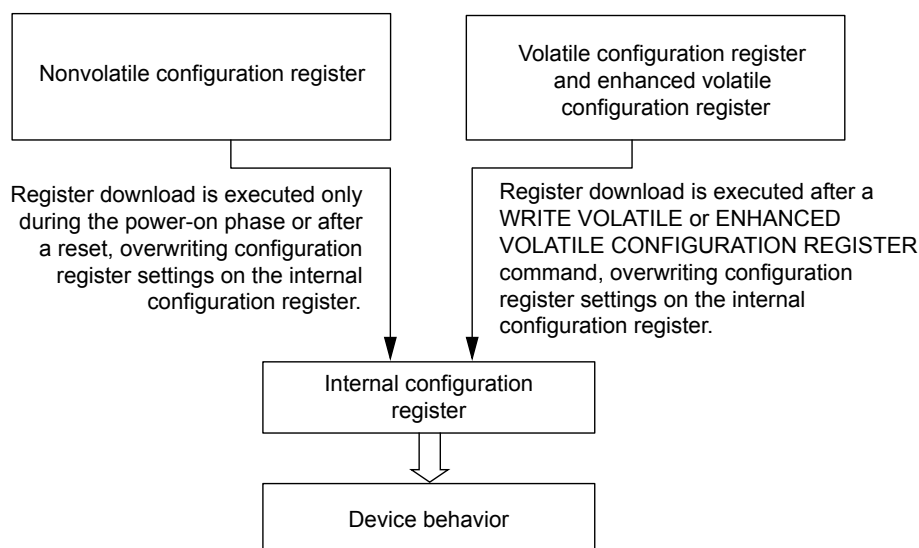
### Internal Configuration Register

The memory configuration is set by an internal configuration register that is not directly accessible to users.

The user can change the default configuration at power up by using the WRITE NON-VOLATILE CONFIGURATION REGISTER. Information from the nonvolatile configuration register overwrites the internal configuration register during power on or after a reset.

The user can change the configuration during operation by using the WRITE VOLATILE CONFIGURATION REGISTER or the WRITE ENHANCED VOLATILE CONFIGURATION REGISTER commands. Information from the volatile configuration registers overwrite the internal configuration register immediately after the WRITE command completes.

**Figure 7: Internal Configuration Register**





## 512Mb, 1.8V Multiple I/O Serial Flash Memory Nonvolatile Configuration Register

### Nonvolatile Configuration Register

The nonvolatile configuration register is read from and written to using the READ NON-VOLATILE CONFIGURATION REGISTER and the WRITE NONVOLATILE CONFIGURATION REGISTER commands, respectively. A register download is executed during power-on or after reset, overwriting the internal configuration register settings that determine device memory behavior.

**Table 7: Nonvolatile Configuration Register**

Bit	Name	Settings	Description	Notes
15:12	Number of dummy clock cycles	0000 = 15 0001 = 1 0010 = 2 . . 1101 = 13 1110 = 14 1111 = 15 (Default)	Sets the number of dummy clock cycles subsequent to all FAST READ commands. The default setting targets the maximum allowed frequency and guarantees backward compatibility.	1
11:9	XIP mode at power-on reset	000 = XIP: Fast read 001 = XIP: Dual output fast read 010 = XIP: Dual I/O fast read 011 = XIP: Quad output fast read 100 = XIP: Quad I/O fast read 101 = Reserved 110 = Reserved 111 = Disabled (Default)	Enables the device to operate in the selected XIP mode immediately after power-on reset.	
8:6	Output driver strength	000 = Reserved 001 = 90 Ohms 010 = Reserved 011 = 45 Ohms 100 = Reserved 101 = 20 Ohms 110 = Reserved 111 = 30 Ohms (Default)	Optimizes the impedance at $V_{CC}/2$ output voltage.	
5	Double transfer rate protocol	0 = Enabled 1 = Disabled (Default)	Set DTR protocol as current one. Once enabled, all commands will work in DTR.	
4	Reset/hold	0 = Disabled 1 = Enabled (Default)	Enables or disables HOLD# or RESET# on DQ3.	
3	Quad I/O protocol	0 = Enabled 1 = Disabled (Default, extended I/O protocol)	Enables or disables quad I/O command input (4-4-4 mode).	2
2	Dual I/O protocol	0 = Enabled 1 = Disabled (Default, extended I/O protocol)	Enables or disables dual I/O command input (2-2-2 mode).	2
1	128Mb segment select	0 = Highest 128Mb segment 1 = Lowest 128Mb segment (Default)	Selects the power-on default 128Mb segment for 3-byte address operations. See also the extended address register.	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Nonvolatile Configuration Register

**Table 7: Nonvolatile Configuration Register (Continued)**

Bit	Name	Settings	Description	Notes
0	Number of address bytes during command entry	0 = Enable 4-byte address mode 1 = Enable 3-byte address mode (Default)	Defines the number of address bytes for a command.	

- Notes:
1. The number of cycles must be set according to and sufficient for the clock frequency, which varies by the type of FAST READ command, as shown in the Supported Clock Frequencies table. An insufficient number of dummy clock cycles for the operating frequency causes the memory to read incorrect data.
  2. When bits 2 and 3 are both set to 0, the device operates in quad I/O protocol.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Volatile Configuration Register

### Volatile Configuration Register

This register is read from and written to by the READ VOLATILE CONFIGURATION REGISTER and the WRITE VOLATILE CONFIGURATION REGISTER commands, respectively. A register download is executed after these commands, overwriting the internal configuration register settings that determine device memory behavior.

**Table 8: Volatile Configuration Register**

Bit	Name	Settings	Description	Notes
7:4	Number of dummy clock cycles	0000 = 15 0001 = 1 0010 = 2 . . 1101 = 13 1110 = 14 1111 = 15 (default)	Sets the number of dummy clock cycles subsequent to all FAST READ commands. The default setting targets maximum allowed frequency and guarantees backward compatibility.	1
3	XIP	0 = Enable 1 = Disable (default)	Enables or disables XIP.	
2	Reserved	0	0b = Fixed value.	
1:0	Wrap	00 = 16-byte boundary aligned 01 = 32-byte boundary aligned 10 = 64-byte boundary aligned 11 = Continuous (default)	16-byte wrap: Output data wraps within an aligned 16-byte boundary starting from the 3-byte address issued after the command code. 32-byte wrap: Output data wraps within an aligned 32-byte boundary starting from the 3-byte address issued after the command code. 64-byte wrap: Output data wraps within an aligned 64-byte boundary starting from the 3-byte address issued after the command code. Continuously sequences addresses through the entire array.	2

- Notes:
1. The number of cycles must be set according to and sufficient for the clock frequency, which varies by the type of FAST READ command, as shown in the Supported Clock Frequencies table. An insufficient number of dummy clock cycles for the operating frequency causes the memory to read incorrect data.
  2. See the Sequence of Bytes During Wrap table.

**Table 9: Sequence of Bytes During Wrap**

Starting Address	16-Byte Wrap	32-Byte Wrap	64-Byte Wrap
0	0-1-2- ... -15-0-1- ..	0-1-2- ... -31-0-1- ..	0-1-2- ... -63-0-1- ..
1	1-2- ... -15-0-1-2- ..	1-2- ... -31-0-1-2- ..	1-2- ... -63-0-1-2- ..
15	15-0-1-2-3- ... -15-0-1- ..	15-16-17- ... -31-0-1- ..	15-16-17- ... -63-0-1- ..
31	31-16-17- ... -31-16-17- ..	31-0-1-2-3- ... -31-0-1- ..	31-32-33- ... -63-0-1- ..
63	63-48-49- ... -63-48-49- ..	63-32-33- ... -63-32-33- ..	63-0-1- ... -63-0-1- ..



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Volatile Configuration Register

### Supported Clock Frequencies

**Table 10: Clock Frequencies – STR (in MHz)**

Note 1 applies to entire table

Number of Dummy Clock Cycles	FAST READ	DUAL OUTPUT FAST READ	DUAL I/O FAST READ	QUAD OUTPUT FAST READ	QUAD I/O FAST READ
1	94	79	60	44	39
2	112	97	77	61	48
3	129	106	86	78	58
4	133	115	97	97	69
5	133	125	106	106	78
6	133	133	115	115	86
7	133	133	125	125	97
8	133	133	133	133	106
9	133	133	133	133	115
10	133	133	133	133	125
11 to 14	133	133	133	133	133

Note: 1. Values are guaranteed by characterization and not 100% tested in production.

**Table 11: Clock Frequencies – DTR (in MHz)**

Note 1 applies to entire table

Number of Dummy Clock Cycles	FAST READ	DUAL OUTPUT FAST READ	DUAL I/O FAST READ	QUAD OUTPUT FAST READ	QUAD I/O FAST READ
1	47	43	30	26	20
2	56	48	38	39	25
3	64	53	43	43	30
4	66	57	48	48	34
5	66	62	53	53	39
6	66	66	57	57	43
7	66	66	62	62	48
8	66	66	66	66	53
9	66	66	66	66	57
10	66	66	66	66	62
11 to 14	66	66	66	66	66

Note: 1. Values are guaranteed by characterization and not 100% tested in production.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Enhanced Volatile Configuration Register

### Enhanced Volatile Configuration Register

This register is read from and written to using the READ ENHANCED VOLATILE CONFIGURATION REGISTER and the WRITE ENHANCED VOLATILE CONFIGURATION REGISTER commands, respectively. A register download is executed after these commands, overwriting the internal configuration register settings that determine device memory behavior.

**Table 12: Enhanced Volatile Configuration Register**

Bit	Name	Settings	Description	Notes
7	Quad I/O protocol	0 = Enabled 1 = Disabled (Default, extended SPI protocol)	Enables or disables quad I/O command input (4-4-4 mode).	1
6	Dual I/O protocol	0 = Enabled 1 = Disabled (Default, extended SPI protocol)	Enables or disables dual I/O command input (2-2-2 mode).	1
5	Double transfer rate protocol	0 = Enabled 1 = Disabled (Default, single transfer rate)	Set DTR protocol as current one. Once enabled, all commands will work in DTR	
4	Reset/hold	0 = Disabled 1 = Enabled (Default)	Enables or disables HOLD# or RESET# on DQ3. (Available only on specified part numbers.)	
3	Reserved	0		
2:0	Output driver strength	000 = Reserved 001 = 90 Ohms 010 = Reserved 011 = 45 Ohms 100 = Reserved 101 = 20 Ohms 110 = Reserved 111 = 30 Ohms (Default)	Optimizes the impedance at $V_{CC}/2$ output voltage.	

Note: 1. When bits 6 and 7 are both set to 0, the device operates in quad I/O protocol. When either bit 6 or 7 is set to 0, the device operates in dual I/O or quad I/O respectively. When a bit is set, the device enters the selected protocol immediately after the WRITE ENHANCED VOLATILE CONFIGURATION REGISTER command. The device returns to the default protocol after the next power-on or reset. Also, the rescue sequence or another WRITE ENHANCED VOLATILE CONFIGURATION REGISTER command will return the device to the default protocol.

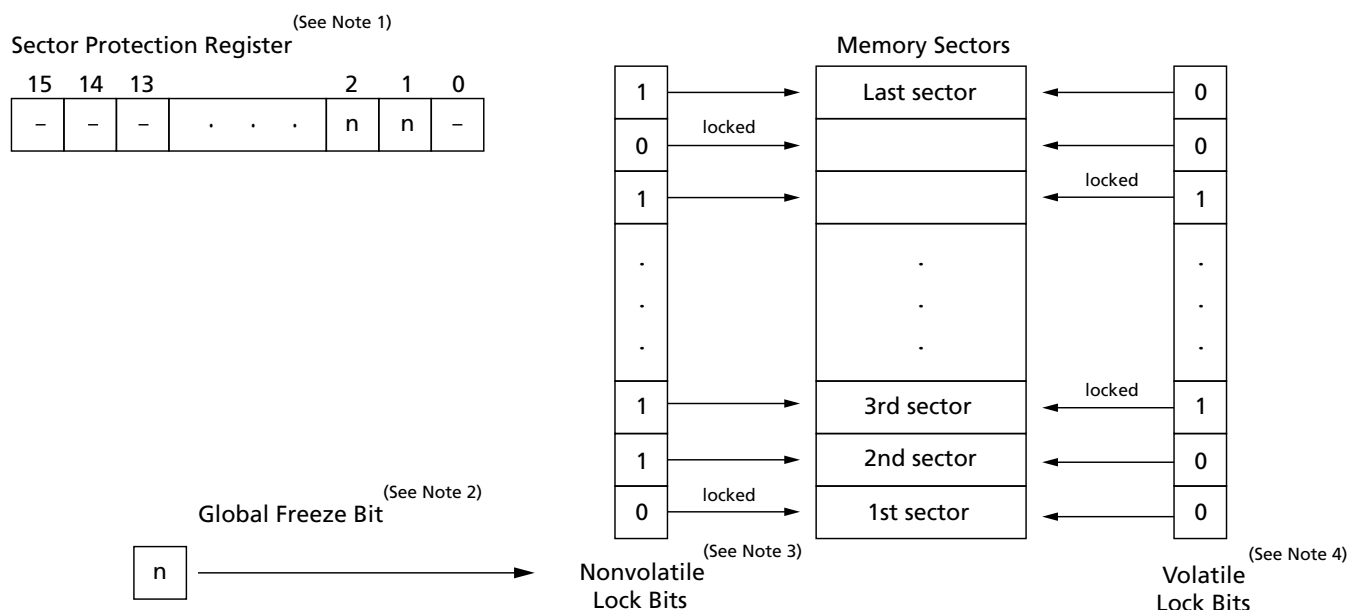


## 512Mb, 1.8V Multiple I/O Serial Flash Memory Security Registers

### Security Registers

Security registers enable sector and password protection on multiple levels using non-volatile and volatile register and bit settings (shown below). The applicable register tables follow.

**Figure 8: Sector and Password Protection**



- Notes:
- Sector protection register.** This 16-bit nonvolatile register includes two active bits[2:1] to enable sector and password protection.
  - Global freeze bit.** This volatile bit protects the settings in all nonvolatile lock bits.
  - Nonvolatile lock bits.** Each nonvolatile bit corresponds to and provides nonvolatile protection for an individual memory sector, which remains locked (protection enabled) until its corresponding bit is cleared to 1.
  - Volatile lock bits.** Each volatile bit corresponds to and provides volatile protection for an individual memory sector, which is locked temporarily (protection is cleared when the device is reset or powered down).
  - Protection granularity is 64KB (1024 sectors).
  - The first and last sectors will have volatile protections at the 4KB subsector level. Each 4KB subsector in these sectors can be individually locked by volatile lock bits setting; nonvolatile protections granularity remain at the sector level.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Sector Protection Security Register

### Sector Protection Security Register

**Table 13: Sector Protection Register**

Bits	Name	Settings	Description	Notes
15:3	Reserved	1 = Default	–	
2	Password protection lock	1 = Disabled (default) 0 = Enabled	<b>Nonvolatile bit:</b> When set to 1, password protection is disabled. When set to 0, password protection is enabled permanently; the 64-bit password cannot be retrieved or reset.	1, 2
1	Sector protection lock	1 = Enabled, with password protection (default) 0 = Enabled, without password protection	<b>Nonvolatile bit:</b> When set to 1, nonvolatile lock bits can be set to lock/unlock their corresponding memory sectors; bit 2 can be set to 0, enabling password protection permanently. When set to 0, nonvolatile lock bits can be set to lock/unlock their corresponding memory sectors; bit 2 must remain set to 1, disabling password protection permanently.	1, 3, 4
0	Reserved	1 = Default	–	

- Notes:
- Bits 2 and 1 are user-configurable, one-time-programmable, and mutually exclusive in that only one of them can be set to 0. It is recommended that one of the bits be set to 0 when first programming the device.
  - The 64-bit password must be programmed and verified before this bit is set to 0 because after it is set, password changes are not allowed, thus providing protection from malicious software. When this bit is set to 0, a 64-bit password is required to reset the global freeze bit from 0 to 1. In addition, if the password is incorrect or lost, the global freeze bit can no longer be set and nonvolatile lock bits cannot be changed. (See the Sector and Password Protection figure and the Global Freeze Bit Definition table).
  - Whether this bit is set to 1 or 0, it enables programming or erasing nonvolatile lock bits (which provide memory sector protection). The password protection bit must be set beforehand because setting this bit will either enable password protection permanently (bit 2 = 0) or disable password protection permanently (bit 1 = 0).
  - By default, all sectors are unlocked when the device is shipped from the factory. Sectors are locked, unlocked, read, or locked down as explained in the Nonvolatile and Volatile Lock Bits table and the Volatile Lock Bit Register Bit Definitions table.

**Table 14: Global Freeze Bit**

Bits	Name	Settings	Description
0	Global freeze bit	1 = Disabled (Default) 0 = Enabled	<b>Volatile bit:</b> When set to 1, all nonvolatile lock bits can be set to enable or disable locking their corresponding memory sectors. When set to 0, nonvolatile lock bits are protected from PROGRAM or ERASE commands. This bit should not be set to 0 until the nonvolatile lock bits are set.

- Note:
- The READ GLOBAL FREEZE BIT command enables reading this bit. When password protection is enabled, this bit is locked upon device power-up or reset. It cannot be changed without the password. After the password is entered, the UNLOCK PASSWORD command resets this bit to 1 enabling programming or erasing the nonvolatile lock bits. After the bits are changed, the WRITE GLOBAL FREEZE BIT command sets this bit to 0, protecting the nonvolatile lock bits from program or erase operations.





## 512Mb, 1.8V Multiple I/O Serial Flash Memory Nonvolatile and Volatile Sector Lock Bits Security

### Nonvolatile and Volatile Sector Lock Bits Security

**Table 15: Nonvolatile and Volatile Lock Bits**

Bit Details	Nonvolatile Lock Bit	Volatile Lock Bit
Description	Each sector of memory has one corresponding non-volatile lock bit	Each sector of memory has one corresponding volatile lock bit; this bit is the sector write lock bit described in the Volatile Lock Bit Register table.
Function	When set to 0, locks and protects its corresponding memory sector from PROGRAM or ERASE operations during device reset or power-down. Because this bit is nonvolatile, the sector remains locked, protection enabled, until the bit is cleared to 1.	When set to 1, locks and protects its corresponding memory sector from PROGRAM or ERASE operations. Because this bit is volatile, protection is temporary. The sector is unlocked, protection disabled, upon device reset or power-down.
Settings	1 = Lock disabled 0 = Lock enabled	0 = Lock disabled 1 = Lock enabled
Enabling protection	The bit is set to 0 by the WRITE NONVOLATILE LOCK BITS command, enabling protection for designated locked sectors. Programming a sector lock bit requires the typical byte programming time.	The bit is set to 1 by the WRITE VOLATILE LOCK BITS command, enabling protection for designated locked sectors.
Disabling protection	All bits are cleared to 1 by the ERASE NONVOLATILE LOCK BITS command, unlocking and disabling protection for all sectors simultaneously. Erasing all sector lock bits requires typical sector erase time.	All bits are set to 0 upon reset or power-down, unlocking and disabling protection for all sectors.
Reading the bit	Bits are read by the READ NONVOLATILE LOCK BITS command.	Bits are read by the READ VOLATILE LOCK BITS command.

### Volatile Lock Bit Security Register

One volatile lock bit register is associated with each sector of memory. It enables the sector to be locked, unlocked, or locked-down with the WRITE VOLATILE LOCK BITS command, which executes only when sector lock down (bit 1) is set to 0. Each register can be read with the READ VOLATILE LOCK BITS command. This register is compatible with and provides the same locking capability as the lock register in the Micron N25Q SPI NOR family.

**Table 16: Volatile Lock Bit Register**

Bit	Name	Settings	Description
7:2	Reserved	0	Bit values are 0.
1	Sector lock down	0 = Lock-down disabled (Default) 1 = Lock-down enabled	<b>Volatile bit:</b> Device always powers-up with this bit set to 0, so that sector lock down and sector write lock bits can be set to 1. When this bit set to 1, neither of the two dynamic protection register bits can be written to until the next power cycle.
0	Sector write lock	0 = Write lock disabled (Default) 1 = Write lock enabled	<b>Volatile bit:</b> Device always powers-up with this bit set to 0, so that PROGRAM and ERASE operations in this sector can be executed and sector content modified. When this bit is set to 1, PROGRAM and ERASE operations in this sector are not executed.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Device ID Data

### Device ID Data

The device ID data shown in the tables here is read by the READ ID and MULTIPLE I/O READ ID operations.

**Table 17: Device ID Data**

Size (Bytes)	Name	Content Value	Assigned By
1	<b>Manufacturer ID</b>	20h	JEDEC
2	<b>Device ID</b>		
	Memory Type	BAh	Manufacturer
	Memory Capacity	20h (512Mb)	
17	<b>Unique ID</b>		
	1 Byte: Length of data to follow	10h	Factory
	2 Bytes: Extended device ID and device configuration information	ID and information such as uniform architecture, and HOLD or RESET functionality	
	14 Bytes: Customized factory data	Optional	

**Table 18: Extended Device ID Data, First Byte**

Bit 7	Bit 6	Bit 5 <sup>1</sup>	Bit 4	Bit 3	Bit 2 <sup>2</sup>	Bit 1	Bit 0
Reserved	Technology 1 = 45nm	1 = Alternate BP scheme 0 = Standard BP scheme	Reserved	HOLD#/RESET#: 0 = HOLD 1 = RESET	Additional HW RESET#: 1 = Available 0 = Not available	Sector size: 00 = Uniform 64KB	

- Notes:
1. For alternate BP scheme information, contact the factory.
  2. Available for specific part numbers. See Part Number Ordering Information for details.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Serial Flash Discovery Parameter Data

### Serial Flash Discovery Parameter Data

Data in these tables is read by the READ SERIAL FLASH DISCOVERY PARAMETER operation.

**Table 19: Serial Flash Discovery Parameter Data**

Compliant with JEDEC standard JC-42.4 1775.03

Description		Address (Byte Mode)	Address (Bit)	Data
SFDP signature		00h	7:0	53h
		01h	7:0	46h
		02h	7:0	44h
		03h	7:0	50h
SFDP revision	Minor	04h	7:0	05h
	Major	05h	7:0	01h
Number of parameter headers		06h	7:0	01h
Unused		07h	7:0	FFh
Parameter ID(0)		08h	7:0	00h
Parameter minor revision		09h	7:0	05h
Parameter major revision		0Ah	7:0	01h
Parameter length (in DW)		0Bh	7:0	10h
Parameter table pointer		0Ch	7:0	30h
		0Dh	7:0	00h
		0Eh	7:0	00h
		0Fh	7:0	FFh
Parameter ID (3)		10h	7:0	03h
Parameter minor revision		11h	7:0	00h
Parameter major revision		12h	7:0	01h
Parameter length (in DW)		13h	7:0	02h
Parameter table pointer		14h	7:0	00h
		15h	7:0	01h
		16h	7:0	00h
Unused		17h	7:0	FFh



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Serial Flash Discovery Parameter Data

**Table 20: Parameter ID**

Description	Byte Address	Bits	Data	Notes
Minimum sector erase sizes	30h	1:0	01b	
Write granularity		2	1	
WRITE ENABLE command required for writing to volatile status registers		3	0	
WRITE ENABLE command selected for writing to volatile status registers		4	0	
Not used		7:5	111b	
4KB ERASE command	31h	7:0	20h	
Supports 1-1-2 FAST READ	32h	0	1	
Address bytes		2:1	01b	
Supports double transfer rate clocking		3	1	
Supports 1-2-2 FAST READ		4	1	
Supports 1-4-4 FAST READ		5	1	
Supports 1-1-4 FAST READ		6	1	
Not used		7	1	
Reserved	33h	7:0	FFh	
Flash size (bits)	34h	7:0	FFh	
	35h	7:0	FFh	
	36h	7:0	FFh	
	37h	7:0	1Fh	
1-4-4 FAST READ dummy cycle count	38h	4:0	01001b	
1-4-4 FAST READ number of mode bits		7:5	001b	
1-4-4 FAST READ command code	39h	7:0	EBh	
1-1-4 FAST READ dummy cycle count	3Ah	4:0	00111b	
1-1-4 FAST READ number of mode bits		7:5	001b	
1-1-4 FAST READ command code	3Bh	7:0	6Bh	
1-1-2 FAST READ dummy cycle count	3Ch	4:0	00111b	
1-1-2 FAST READ number of mode bits		7:5	001b	
1-1-2 FAST READ command	3Dh	7:0	3Bh	
1-2-2 FAST READ dummy cycle count	3Eh	4:0	00111b	
1-2-2 FAST READ number of mode bits		7:5	001b	
1-2-2 Command code	3Fh	7:0	BBh	
Supports 2-2-2 FAST READ	40h	0	1	
Reserved		3:1	111b	
Supports 4-4-4 FAST READ		4	1	
Reserved		7:5	111b	
Reserved	43:41h	31:8	FFFFFFh	
Reserved	45:44h	15:0	FFFFh	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Serial Flash Discovery Parameter Data

**Table 20: Parameter ID (Continued)**

Description	Byte Address	Bits	Data	Notes
2-2-2 FAST READ dummy cycle count	46h	4:0	00111b	
2-2-2 FAST READ number of mode bits		7:5	001b	
2-2-2 FAST READ command code	47h	7:0	BBh	
Reserved	49:48h	15:0	FFFFh	
4-4-4 FAST READ dummy cycle count	4Ah	4:0	01001b	
4-4-4 FAST READ number of mode bits		7:5	001b	
4-4-4 FAST READ command code	4Bh	7:0	EBh	
Sector Type 1 size	4Ch	7:0	0Ch	
Sector Type 1 command code	4Dh	7:0	20h	
Sector Type 2 size	4Eh	7:0	10h	
Sector Type 2 code	4Fh	7:0	D8h	
Sector Type 3 size	50h	7:0	0Fh	
Sector Type 3 code	51h	7:0	52h	
Sector Type 4 size	52h	7:0	00h	
Sector Type 4 code	53h	7:0	00h	
Multiplier from typical erase time to maximum erase time	57h:54h	3:0	0100b	
Sector Type 1 ERASE time (TYP)		8:4	00010b	
		10:9	01b	
Sector Type 2 ERASE time (TYP)		15:11	01001b	
		17:16	01b	
Sector Type 3 ERASE time (TYP)		22:18	00110b	
		24:23	01b	
Sector Type 4 ERASE time (TYP)		29:25	00000b	
		31:30	00b	
Multiplier from typical time to maximum time for page or byte PROGRAM	5Bh:58h	3:0	1011b	
Page size		7:4	1000b	
Page PROGRAM time (TYP)		12:8	1110b	
		13	0b	
		17:14	1110b	
Byte PROGRAM time, first byte (TYP)		18	0b	
		22:19	0000b	
		23	0b	1
Chip ERASE time (TYP)		28:24	00001b	
		30:29	11b	
Reserved		31	1b	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Serial Flash Discovery Parameter Data

**Table 20: Parameter ID (Continued)**

Description	Byte Address	Bits	Data	Notes
Prohibited operations during PROGRAM SUSPEND	5Fh:5Ch	3:0	1100b	
Prohibited operations during ERASE SUSPEND		7:4	0110b	
Reserved		8	1b	
PROGRAM RESUME to SUSPEND interval		12:9	0000b	2
SUSPEND in progress program maximum latency		17:13	11000b	
		19:18	1100b	
ERASE RESUME to SUSPEND interval		23:20	0010b	
SUSPEND in progress erase maximum latency		28:24	11000b	
		30:29	01b	
SUSPEND RESUME supported		31	0b	
PROGRAM RESUME command	60h	7:0	7Ah	
PROGRAM SUSPEND command	61h	7:0	75h	
RESUME command	62h	7:0	7Ah	
SUSPEND command	63h	7:0	75h	
Reserved	67h:64h	1:0	11b	
Status register polling device busy		2	0b	
		3	1b	
		7:4	1111b	
EXIT DEEP POWER-DOWN to next operation delay		12:8	11101b	
		14:13	01b	
EXIT DEEP POWER-DOWN command		22:15	ABh	
ENTER DEEP POWER-DOWN command		30:23	B9h	
Deep power-down supported		31	0h	
4-4-4 mode disable sequence	68h:68h	3:0	1010b	
4-4-4 mode enable sequence		8:4	1_0100b	
0-4-4 mode supported		9	1b	
0-4-4 mode exit method		15:10	00_0011b	
0-4-4 mode entry method		19:16	0010b	
Quad enable requirements		22:20	000b	
HOLD and WP disable		23	1bh	
Reserved		31:24	FFh	
Volatile and nonvolatile register and WRITE ENABLE	6Fh: 6Ch	6:0	0000001b	
Reserved		7	1b	
Soft reset and rescue sequence support		13:8	111101b	
EXIT 4-BYTE ADDRESS		23:14	00_1111_0110h	
ENTER 4-BYTE ADDRESS		31:24	0011_0110b	

Notes: 1. Per industry standards, 1μs is the minimum allowed. See the AC Characteristics and Operating Conditions for specification details.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Serial Flash Discovery Parameter Data

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2. Per industry standards, 64 $\mu$ s is the minimum allowed. See the AC Characteristics and Operating Conditions for specification details.

## Command Definitions

**Table 21: Command Set**

Notes 1 and 2 apply to the entire table

Notes 1 and 2 apply to the entire table

Command	Code	Command/Address			Address Bytes	Dummy Clock Cycles		
		Extended SPI	Dual SPI	Quad SPI		Extended SPI	Dual SPI	Quad SPI
Software RESET Operations								
RESET ENABLE	66h	1-0-0	2-0-0	4-0-0	0	0	0	0
RESET MEMORY	99h	1-0-0	2-0-0	4-0-0	0	0	0	0
READ ID Operations								
READ ID	9E/9Fh	1-0-1			0	0		
MULTIPLE I/O READ ID	AFh	1-0-1	2-0-2	4-0-4	0	0	0	0
READ SERIAL FLASH DISCOVERY PARAMETER	5Ah	1-1-1	2-2-2	4-4-4	3	8	8	8
READ MEMORY Operations								
READ	03h	1-1-1	2-2-2	4-4-4	3(4)	0	0	0
FAST READ	0Bh	1-1-1	2-2-2	4-4-4	3(4)	8	8	10
DUAL OUTPUT FAST READ	3Bh	1-1-2	2-2-2		3(4)	8	8	
DUAL INPUT/OUTPUT FAST READ	BBh	1-2-2	2-2-2		3(4)	8	8	
QUAD OUTPUT FAST READ	6Bh	1-1-4		4-4-4	3(4)	8		10
QUAD INPUT/OUTPUT FAST READ	EBh	1-4-4		4-4-4	3(4)	10		10
DTR FAST READ	0Dh	1-1-1	2-2-2	4-4-4	3(4)	6	6	8
DTR DUAL OUTPUT FAST READ	3Dh	1-1-2	2-2-2		3(4)	6	6	
DTR DUAL INPUT/OUTPUT FAST READ	BDh	1-2-2	2-2-2		3(4)	6	6	
DTR QUAD OUTPUT FAST READ	6Dh	1-1-4		4-4-4	3(4)	6		8
DTR QUAD INPUT/OUTPUT FAST READ	EDh	1-4-4		4-4-4	3(4)	8		8
QUAD INPUT/OUTPUT WORD READ	E7h	1-4-4		4-4-4	3(4)	4		4
READ MEMORY Operations with 4-Byte Address								
4-BYTE READ	13h	1-1-1	2-2-2	4-4-4	4	0	0	0
4-BYTE FAST READ	0Ch	1-1-1	2-2-2	4-4-4	4	8	8	10
4-BYTE DUAL OUTPUT FAST READ	3Ch	1-1-2	2-2-2		4	8	8	



**Table 21: Command Set (Continued)**

Notes 1 and 2 apply to the entire table

Command	Code	Command/Address			Address Bytes	Dummy Clock Cycles		
		Extended SPI	Dual SPI	Quad SPI		Extended SPI	Dual SPI	Quad SPI
4-BYTE DUAL INPUT/OUTPUT FAST READ	BCh	1-2-2	2-2-2		4	8	8	
4-BYTE QUAD OUTPUT FAST READ	6Ch	1-1-4		4-4-4	4	8		10
4-BYTE QUAD INPUT/OUTPUT FAST READ	ECh	1-4-4		4-4-4	4	10		10
4-BYTE DTR FAST READ	0Eh	1-1-1	2-2-2	4-4-4	4	6	6	8
4-BYTE DTR DUAL INPUT/OUTPUT FAST READ	BEh	1-2-2	2-2-2		4	6	6	
4-BYTE DTR QUAD INPUT/OUTPUT FAST READ	EEh	1-4-4		4-4-4	4	8		8
<b>WRITE Operations</b>								
WRITE ENABLE	06h	1-0-0	2-0-0	4-0-0	0	0	0	0
WRITE DISABLE	04h	1-0-0	2-0-0	4-0-0	0	0	0	0
<b>READ REGISTER Operations</b>								
READ STATUS REGISTER	05h	1-0-1	2-0-2	4-0-4	0	0	0	0
READ FLAG STATUS REGISTER	70h	1-0-1	2-0-2	4-0-4	0	0	0	0
CLEAR FLAG STATUS REGISTER	50h	1-0-0	2-0-0	4-0-0	0	0	0	0
READ NONVOLATILE CONFIGURATION REGISTER	B5h	1-0-1	2-0-2	4-0-4	0	0	0	0
READ VOLATILE CONFIGURATION REGISTER	85h	1-0-1	2-0-2	4-0-4	0	0	0	0
READ ENHANCED VOLATILE CONFIGURATION REGISTER	65h	1-0-1	2-0-2	4-0-4	0	0	0	0
READ EXTENDED ADDRESS REGISTER	C8h	1-0-1	2-0-2	4-0-4	0	0	0	0
<b>WRITE REGISTER Operations</b>								
WRITE STATUS REGISTER	01h	1-0-1	2-0-2	4-0-4	0	0	0	0
WRITE NONVOLATILE CONFIGURATION REGISTER	B1h	1-0-1	2-0-2	4-0-4	0	0	0	0

**Table 21: Command Set (Continued)**

Notes 1 and 2 apply to the entire table

Command	Code	Command/Address			Address Bytes	Dummy Clock Cycles		
		Extended SPI	Dual SPI	Quad SPI		Extended SPI	Dual SPI	Quad SPI
WRITE VOLATILE CONFIGURATION REGISTER	81h	1-0-1	2-0-2	4-0-4	0	0	0	0
WRITE ENHANCED VOLATILE CONFIGURATION REGISTER	61h	1-0-1	2-0-2	4-0-4	0	0	0	0
WRITE EXTENDED ADDRESS REGISTER	C5h	1-0-1	2-0-2	4-0-4	0	0	0	0
<b>PROGRAM Operations</b>								
PAGE PROGRAM	02h	1-1-1	2-2-2	4-4-4	3(4)	0	0	0
DUAL INPUT FAST PROGRAM	A2h	1-1-2	2-2-2		3(4)	0	0	
EXTENDED DUAL INPUT FAST PROGRAM	D2h	1-2-2	2-2-2		3(4)	0	0	
QUAD INPUT FAST PROGRAM	32h	1-1-4		4-4-4	3(4)	0		0
EXTENDED QUAD INPUT FAST PROGRAM	38h	1-4-4		4-4-4	3(4)	0		0
<b>PROGRAM Operations with 4-Byte Address</b>								
4-BYTE PAGE PROGRAM	12h	1-1-1	2-2-2	4-4-4	4	0	0	0
4-BYTE QUAD INPUT FAST PROGRAM	34h	1-1-4		4-4-4	4	0		0
4-BYTE QUAD INPUT EXTENDED FAST PROGRAM	3Eh	1-4-4		4-4-4	4	0		0
<b>ERASE Operations</b>								
32KB SUBSECTOR ERASE	52h	1-1-0	2-2-0	4-4-0	3(4)	0	0	0
4KB SUBSECTOR ERASE	20h	1-1-0	2-2-0	4-4-0	3(4)	0	0	0
SECTOR ERASE	D8h	1-1-0	2-2-0	4-4-0	3(4)	0	0	0
Bulk ERASE	C7h	1-0-0	2-0-0	4-0-0	0	0	0	0
<b>ERASE Operations with 4-Byte Address</b>								
4-BYTE SECTOR ERASE	DCh	1-1-0	2-2-0	4-4-0	4	0	0	0
4-BYTE 4KB SUBSECTOR ERASE	21h	1-1-0	2-2-0	4-4-0	4	0	0	0
<b>SUSPEND/RESUME Operations</b>								
PROGRAM/ERASE SUSPEND	75h	1-0-0	2-0-0	4-0-0	0	0	0	0
PROGRAM/ERASE RESUME	7Ah	1-0-0	2-0-0	4-0-0	0	0	0	0

**Table 21: Command Set (Continued)**

Notes 1 and 2 apply to the entire table

Notes 1 and 2 apply to the entire table

Command	Code	Command/Address			Address Bytes	Dummy Clock Cycles		
		Extended SPI	Dual SPI	Quad SPI		Extended SPI	Dual SPI	Quad SPI
ONE-TIME PROGRAMMABLE (OTP) Operations								
READ OTP ARRAY	4Bh	1-1-1	2-2-2	4-4-4	3(4)	8	8	10
PROGRAM OTP ARRAY	42h	1-1-1	2-2-2	4-4-4	3(4)	0	0	0
4-BYTE ADDRESS MODE Operations								
ENTER 4-BYTE ADDRESS MODE	B7h	1-0-0	2-0-0	4-0-0	0	0	0	0
EXIT 4-BYTE ADDRESS MODE	E9h	1-0-0	2-0-0	4-0-0	0	0	0	0
QUAD PROTOCOL Operations								
ENTER QUAD INPUT/OUTPUT MODE	35h	1-0-0	2-0-0	4-0-0	0	0	0	0
RESET QUAD INPUT/OUTPUT MODE	F5h	1-0-0	2-0-0	4-0-0	0	0	0	0
Deep Power-Down Operations								
ENTER DEEP POWER DOWN	B9h	1-0-0	2-0-0	4-0-0	0	0	0	0
RELEASE FROM DEEP POWER-DOWN	ABh	1-0-0	2-0-0	4-0-0	0	0	0	0
ADVANCED SECTOR PROTECTION Operations								
READ SECTOR PROTECTION	2Dh	1-0-1	2-0-2	4-0-4	0	0	0	0
PROGRAM SECTOR PROTECTION	2Ch	1-0-1	2-0-2	4-0-4	0	0	0	0
READ VOLATILE LOCK BITS	E8h	1-1-1	2-2-2	4-4-4	3(4)	0	0	0
WRITE VOLATILE LOCK BITS	E5h	1-1-1	2-2-2	4-4-4	3(4)	0	0	0
READ NONVOLATILE LOCK BITS	E2h	1-1-1	2-2-2	4-4-4	4	0	0	0
WRITE NONVOLATILE LOCK BITS	E3h	1-1-0	2-2-0	4-4-0	4	0	0	0
ERASE NONVOLATILE LOCK BITS	E4h	1-0-0	2-0-0	4-0-0	0	0	0	0
READ GLOBAL FREEZE BIT	A7h	1-0-1			0	0	0	0
WRITE GLOBAL FREEZE BIT	A6h	1-0-0	2-0-0	4-0-0	0	0	0	0
READ PASSWORD	27h	1-0-1			0	0	0	0
WRITE PASSWORD	28h	1-0-1	2-0-2	4-0-4	0	0	0	0
UNLOCK PASSWORD	29h	1-0-1	2-0-2	4-0-4	0	0	0	0
ADVANCED SECTOR PROTECTION Operations with 4-Byte Address								

**Table 21: Command Set (Continued)**

Notes 1 and 2 apply to the entire table

Command	Code	Command/Address			Address Bytes	Dummy Clock Cycles		
		Extended SPI	Dual SPI	Quad SPI		Extended SPI	Dual SPI	Quad SPI
4-BYTE READ VOLATILE LOCK BITS	E0h	1-1-1	2-2-2	4-4-4	4	0	0	0
4-BYTE WRITE VOLATILE LOCK BITS	E1h	1-1-1	2-2-2	4-4-4	4	0	0	0
<b>ADVANCED FUNCTION INTERFACE Operations</b>								
INTERFACE ACTIVATION	9Bh	1-0-0	2-0-0	4-0-0	0	0	0	0
CYCLIC REDUNDANCY CHECK	9Bh/27h	1-0-1	2-0-2	4-0-4	0	0	0	0



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Command Definitions

- Notes:
1. Micron extended SPI protocol is the standard SPI protocol with additional commands that extend functionality and enable address or data transmission on multiple DQn lines.
  2. The command code is always transmitted on DQn = 1, 2, or 4 lines according to the standard, dual, or quad protocol respectively. However, a command may be able to transmit address and data on multiple DQn lines regardless of protocol. The protocol columns show the number of DQn lines a command uses to transmit command, address, and data information as shown in these examples: command-address-data = 1-1-1, or 1-2-2, or 2-4-4, and so on.
  3. The READ SERIAL FLASH DISCOVERY PARAMETER operation accepts only 3-byte address even if the device is configured to 4-byte address mode.
  4. Requires 4 bytes of address if the device is configured to 4-byte address mode.
  5. The number of dummy clock cycles required when shipped from Micron factories. The user can modify the dummy clock cycle number via the nonvolatile configuration register and the volatile configuration register.
  6. The WRITE ENABLE command must be issued first before this operation can be executed.
  7. Formerly referred to as the READ LOCK REGISTER operation.
  8. Formerly referred to as the WRITE LOCK REGISTER operation.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Software RESET Operations

### Software RESET Operations

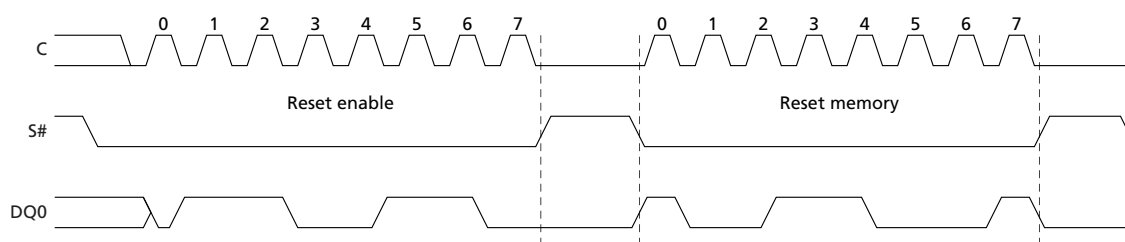
#### RESET ENABLE and RESET MEMORY Commands

To initiate these commands, S# is driven LOW and the command code is input on DQ0. A minimum de-selection time of  $t_{SHSL2}$  must come between RESET ENABLE and RESET MEMORY or reset is not guaranteed. Then, S# must be driven HIGH for the device to enter power-on reset. A time of  $t_{SHSL3}$  is required before the device can be re-selected by driving S# LOW.

**Table 22: RESET ENABLE and RESET MEMORY Operations**

Operation Name	Description/Conditions
RESET ENABLE (66h)	<p>To reset the device, the RESET ENABLE command must be followed by the RESET MEMORY command. When the two commands are executed, the device enters a power-on reset condition. It is recommended to exit XIP mode before executing these two commands.</p> <p>All volatile lock bits, the volatile configuration register, the enhanced volatile configuration register, and the extended address register are reset to the power-on reset default condition according to nonvolatile configuration register settings.</p> <p>If a reset is initiated while a WRITE, PROGRAM, or ERASE operation is in progress or suspended, the operation is aborted and data may be corrupted.</p> <p>Reset is effective after the flag status register bit 7 outputs 1 with at least one byte output.</p> <p>A RESET ENABLE command is not accepted during WRITE STATUS REGISTER and WRITE NONVOLATILE CONFIGURATION REGISTER operations.</p>
RESET MEMORY (99h)	

**Figure 9: RESET ENABLE and RESET MEMORY Command**



Note: 1. The number of lines and rate for transmission varies with extended, dual, or quad SPI.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ ID Operations

### READ ID Operations

#### READ ID and MULTIPLE I/O READ ID Commands

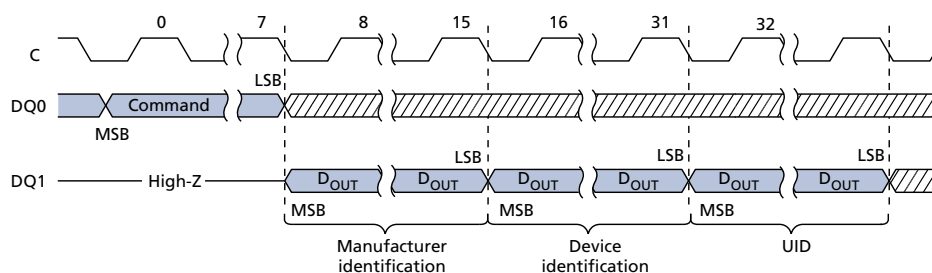
To initiate these commands, S# is driven LOW and the command code is input on DQn. When S# is driven HIGH, the device goes to standby. The operation is terminated by driving S# HIGH at any time during data output.

**Table 23: READ ID and MULTIPLE I/O READ ID Operations**

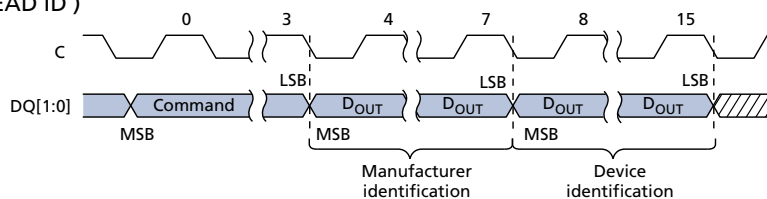
Operation Name	Description/Conditions
READ ID (9Eh/9F)	Outputs information shown in the Device ID Data tables. If an ERASE or PROGRAM cycle is in progress when the command is initiated, the command is not decoded and the command cycle in progress is not affected.
MULTIPLE I/O READ ID (AFh)	

**Figure 10: READ ID and MULTIPLE I/O READ ID Commands**

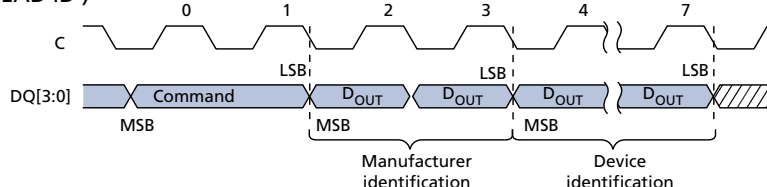
Extended (READ ID)



Dual (MULTIPLE I/O READ ID)



Quad (MULTIPLE I/O READ ID)



Don't Care

Note: 1. S# not shown.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ SERIAL FLASH DISCOVERY PARAMETER Operation

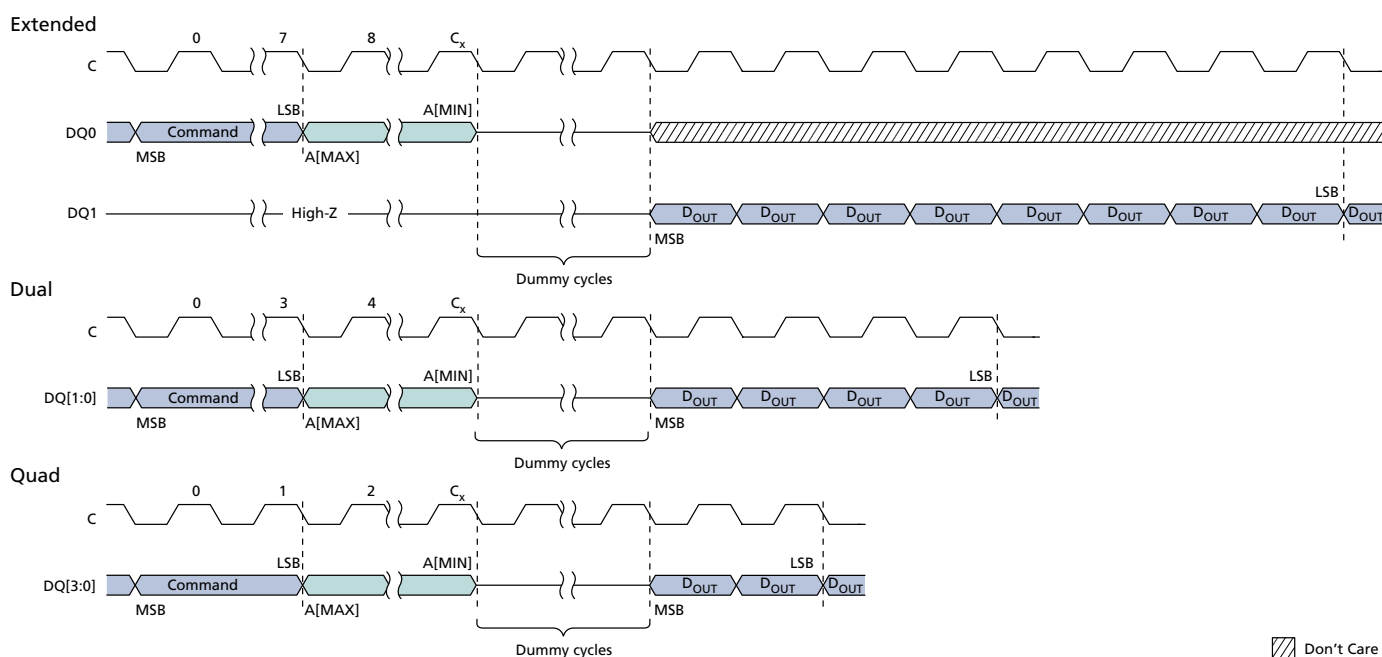
### READ SERIAL FLASH DISCOVERY PARAMETER Operation

#### READ SERIAL FLASH DISCOVERY PARAMETER Command

To execute READ SERIAL FLASH DISCOVERY PARAMETER command, S# is driven LOW. The command code is input on DQ0, followed by three address bytes and eight dummy clock cycles (address is always 3 bytes, even if the device is configured to work in 4-byte address mode). The device outputs the information starting from the specified address. When the 2048-byte boundary is reached, the data output wraps to address 0 of the serial Flash discovery parameter table. The operation is terminated by driving S# HIGH at any time during data output.

**Note:** The operation always executes in continuous mode so the read burst wrap setting in the volatile configuration register does not apply.

**Figure 11: READ SERIAL FLASH DISCOVERY PARAMETER Command – 5Ah**







## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations

### READ MEMORY Operations

To initiate a command, S# is driven LOW and the command code is input on DQ $n$ , followed by input of the address bytes on DQ $n$ . The operation is terminated by driving S# HIGH at any time during data output.

**Table 24: READ MEMORY Operations**

Operation Name	Description/Conditions
READ (03h)	The device supports 3-bytes addressing (default), with A[23:0] input during address cycle. After any READ command is executed, the device will output data from the selected address. After the boundary is reached, the device will start reading again from the beginning.
FAST READ (0Bh)	
DUAL OUTPUT FAST READ (3Bh)	
DUAL INPUT/OUTPUT FAST READ (BBh)	Each address bit is latched in during the rising edge of the clock. The addressed byte can be at any location, and the address automatically increments to the next address after each byte of data is shifted out; therefore, a die can be read with a single command.
QUAD OUTPUT FAST READ (6Bh)	
QUAD INPUT/OUTPUT FAST READ (EBh)	
DTR FAST READ (0Dh)	FAST READ can operate at a higher frequency ( $f_c$ ). DTR commands function in DTR mode regardless of settings in the nonvolatile configuration register or enhanced volatile configuration register; other commands function in DTR mode only after DTR mode is enabled by the register settings.
DTR DUAL OUTPUT FAST READ (3Dh)	
DTR DUAL INPUT/OUTPUT FAST READ (BDh)	
DTR QUAD OUTPUT FAST READ (6Dh)	E7h is similar to the QUAD I/O FAST READ command except that the lowest address bit (A0) must equal 0 and only four dummy clocks are required prior to the data output. This command is supported in extended-SPI, QIO-SPI protocols; the device ignores it in DIO-SPI protocol, and does not support the DTR model.
DTR QUAD INPUT/OUTPUT FAST READ (EDh)	
QUAD INPUT/OUTPUT WORD READ (E7h)	

### 4-BYTE READ MEMORY Operations

**Table 25: 4-BYTE READ MEMORY Operations**

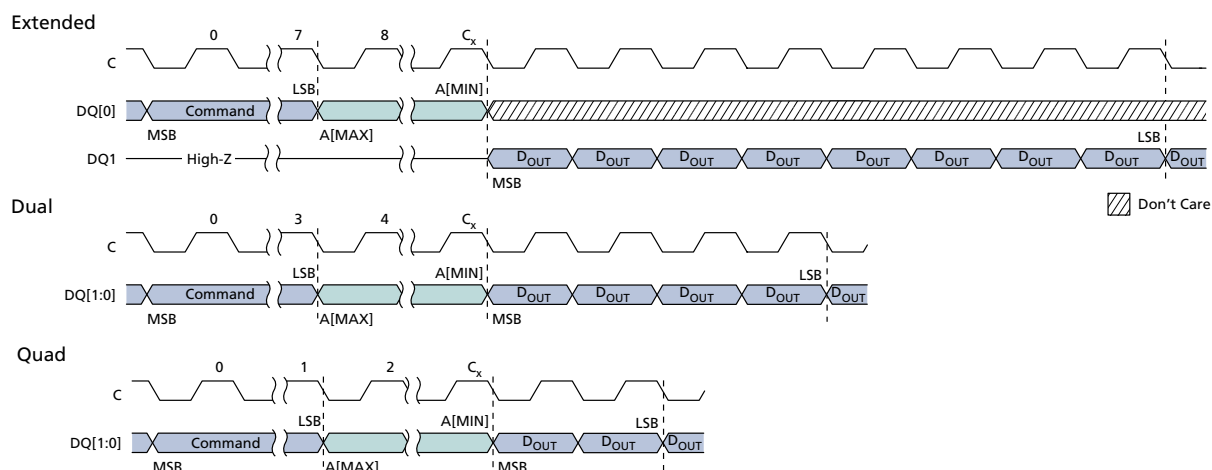
Operation Name	Description/Conditions
4-BYTE READ (13h)	READ MEMORY operations can be extended to a 4-bytes address range, with [A31:0] input during address cycle. Selection of the 3-byte or 4-byte address range can be enabled in two ways: through the nonvolatile configuration register or through the ENABLE 4-BYTE ADDRESS MODE/EXIT 4-BYTE ADDRESS MODE commands.
4-BYTE FAST READ (0Ch)	
4-BYTE DUAL OUTPUT FAST READ (3Ch)	
4-BYTE DUAL INPUT/OUTPUT FAST READ (BCh)	Each address bit is latched in during the rising edge of the clock. The addressed byte can be at any location, and the address automatically increments to the next address after each byte of data is shifted out; therefore, a die can be read with a single command.
4-BYTE QUAD OUTPUT FAST READ (6Ch)	
4-BYTE QUAD INPUT/OUTPUT FAST READ (ECh)	
DTR 4-BYTE FAST READ (0Eh)	FAST READ can operate at a higher frequency ( $f_c$ ). 4-BYTE commands and DTR 4-BYTE commands function in 4-BYTE and DTR 4-BYTE mode regardless of settings in the nonvolatile configuration register or enhanced volatile configuration register; other commands function in 4-BYTE and DTR modes only after the mode is enabled by the register settings.
DTR 4-BYTE DUAL INPUT/OUTPUT FAST READ (BEh)	
DTR 4-BYTE QUAD INPUT/OUTPUT FAST READ (EEh)	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings

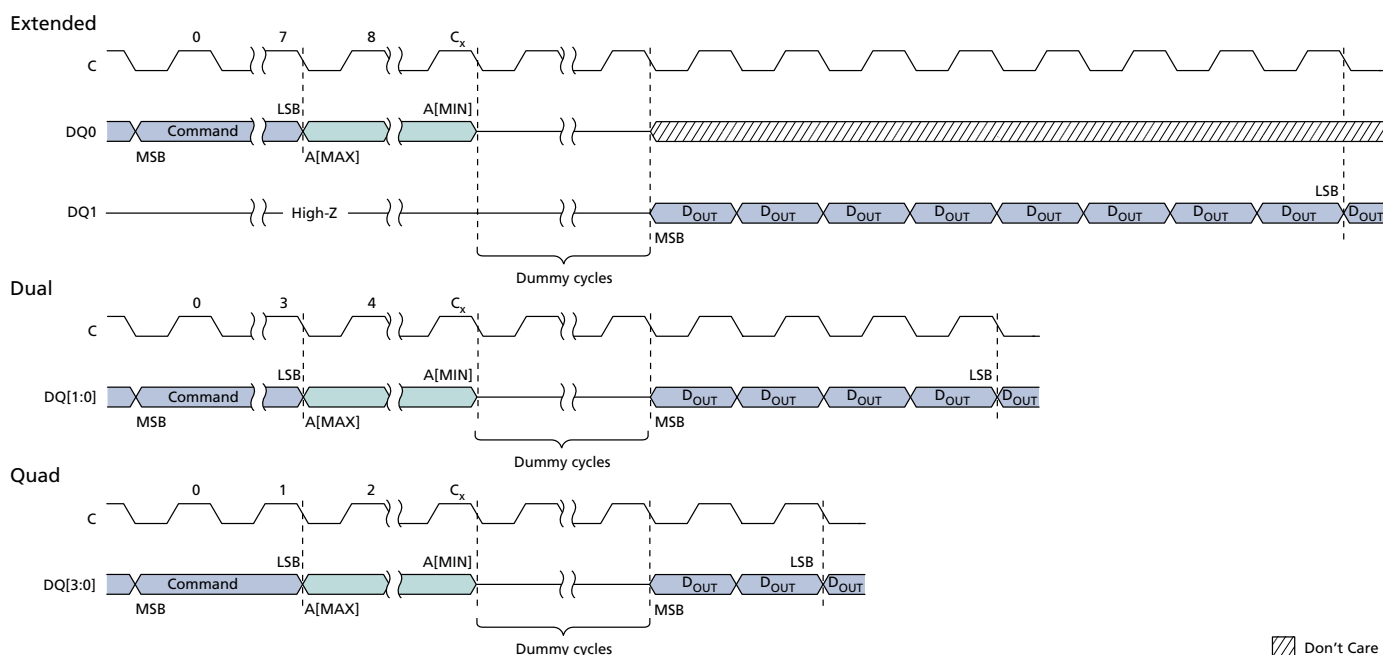
### READ MEMORY Operations Timings

**Figure 12: READ – 03h/13h<sup>3</sup>**



- Notes:
1. For extended protocol,  $C_x = 7 + (A[\text{MAX}] + 1)$ ; For dual protocol,  $C_x = 3 + (A[\text{MAX}] + 1)/2$ ; For quad protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .
  2. S# not shown.
  3. READ and 4-BYTE READ commands.

**Figure 13: FAST READ – 0Bh/0Ch<sup>3</sup>**





## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings

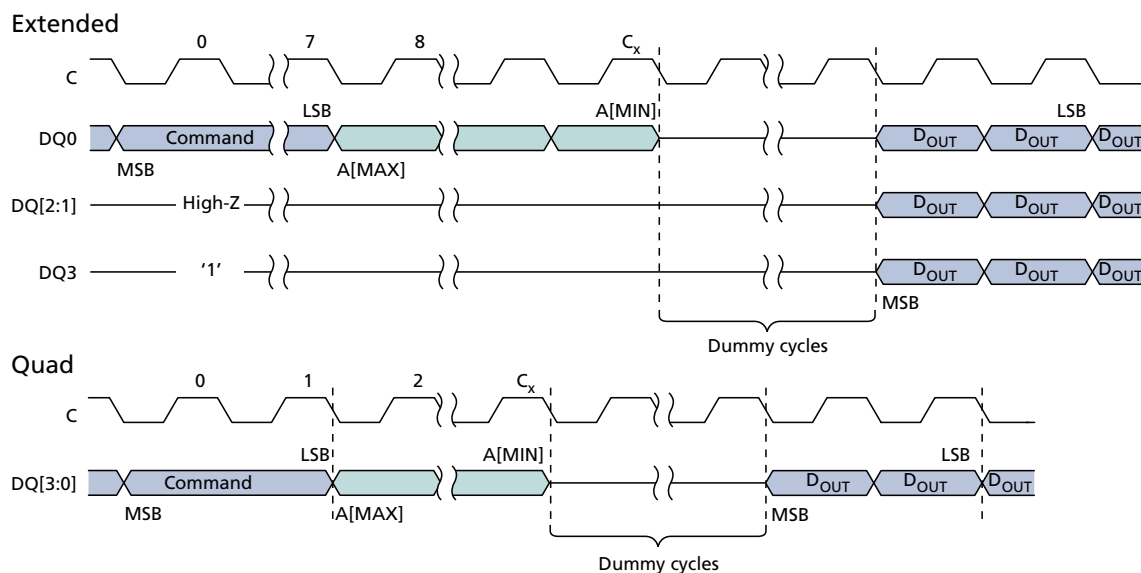
- Notes:
1. For extended protocol,  $C_x = 7 + (A[\text{MAX}] + 1)$ ; For dual protocol,  $C_x = 3 + (A[\text{MAX}] + 1)/2$ ; For quad protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .
  2. S# not shown.
  3. FAST READ and 4-BYTE FAST READ commands.





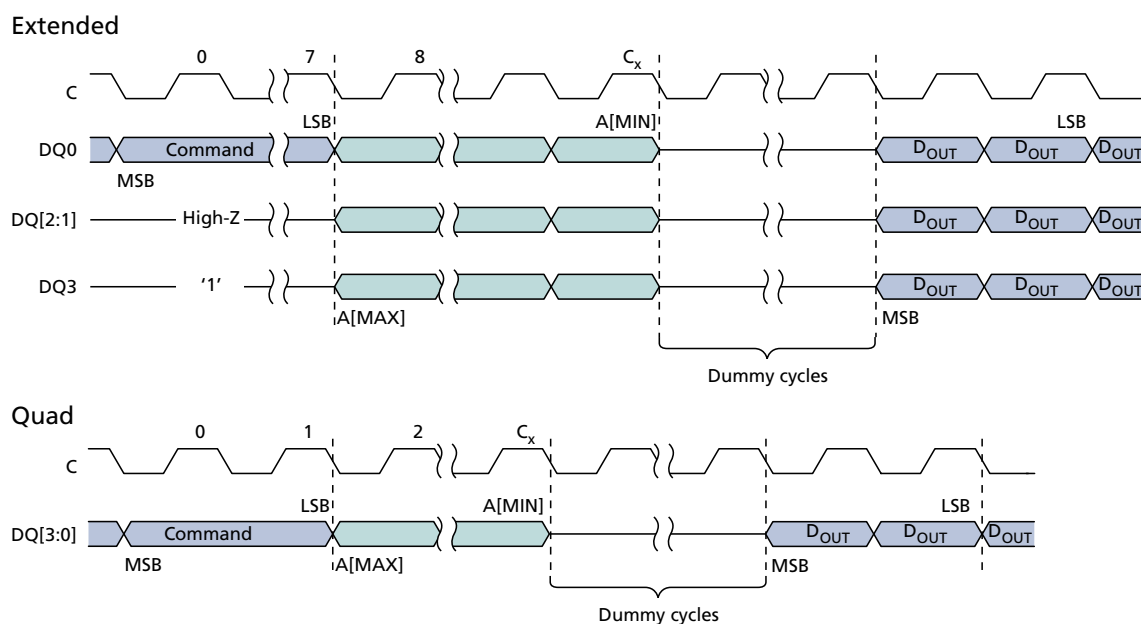
## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings

**Figure 16: QUAD OUTPUT FAST READ – 6Bh<sup>3</sup>**



- Notes:
1. For extended protocol,  $C_x = 7 + (A[MAX] + 1)$ ; For quad protocol,  $C_x = 1 + (A[MAX] + 1)/4$ .
  2. S# not shown.
  3. QUAD OUTPUT FAST READ and 4-BYTE QUAD OUTPUT FAST READ commands.

**Figure 17: QUAD INPUT/OUTPUT FAST READ – EBh<sup>3</sup>**

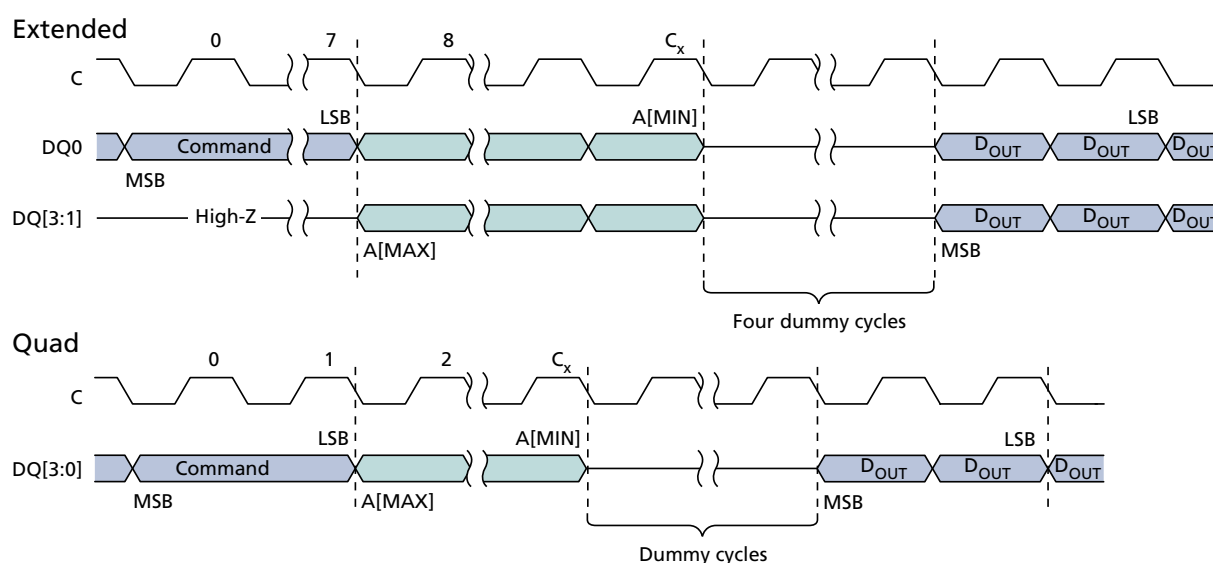




## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings

- Notes:
1. For extended protocol,  $C_x = 7 + (A[\text{MAX}] + 1)/4$ ; For quad protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .
  2. S# not shown.
  3. QUAD INPUT/OUTPUT FAST READ and 4-BYTE QUAD INPUT/OUTPUT FAST READ commands.

**Figure 18: QUAD INPUT/OUTPUT WORD READ – E7h<sup>3</sup>**

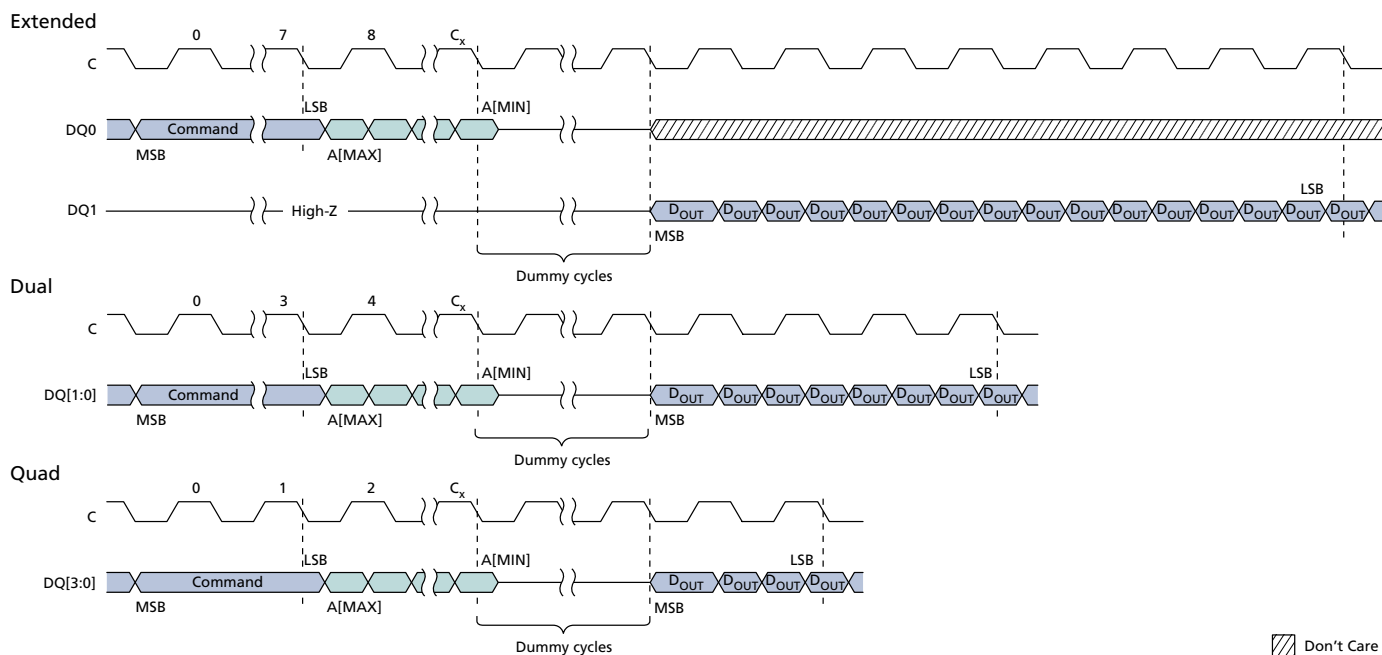


- Notes:
1. In quad SPI protocol, the command, address, and data-out bits are transmitted on all four data pins.
  2. For extended protocol,  $C_x = 7 + (A[\text{MAX}] + 1)/4$ ; For quad protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .
  3. S# not shown.
  4. QUAD INPUT/OUTPUT WORD READ and 4-BYTE QUAD INPUT/OUTPUT WORD READ commands.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings

**Figure 19: DTR FAST READ – 0Dh<sup>3</sup>**

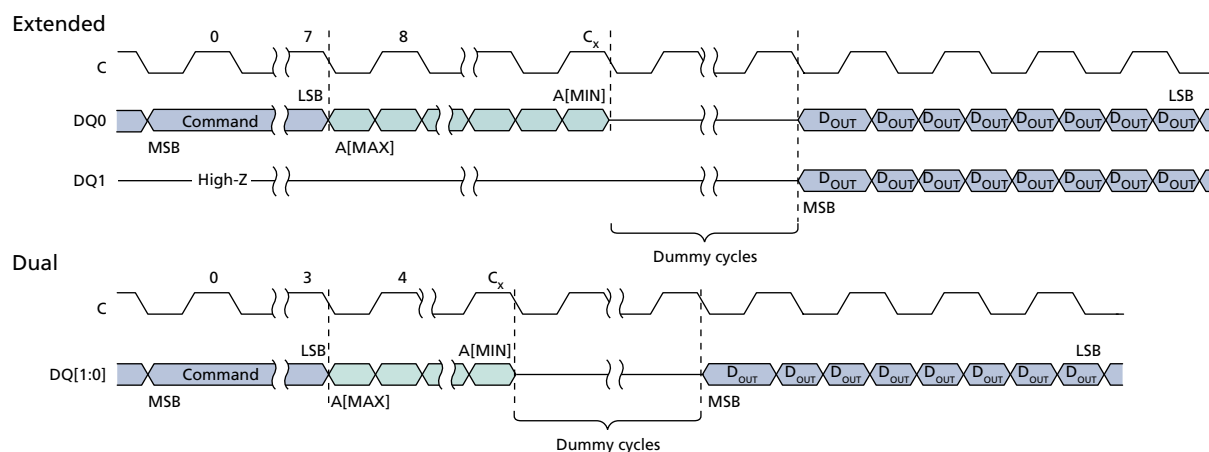


- Notes:
1. For extended protocol,  $C_x = 7 + (A[\text{MAX}] + 1)/2$ ; For dual protocol,  $C_x = 3 + (A[\text{MAX}] + 1)/4$ ; For quad protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/8$ .
  2. S# not shown.
  3. DTR FAST READ and 4-BYTE DTR FAST READ commands.



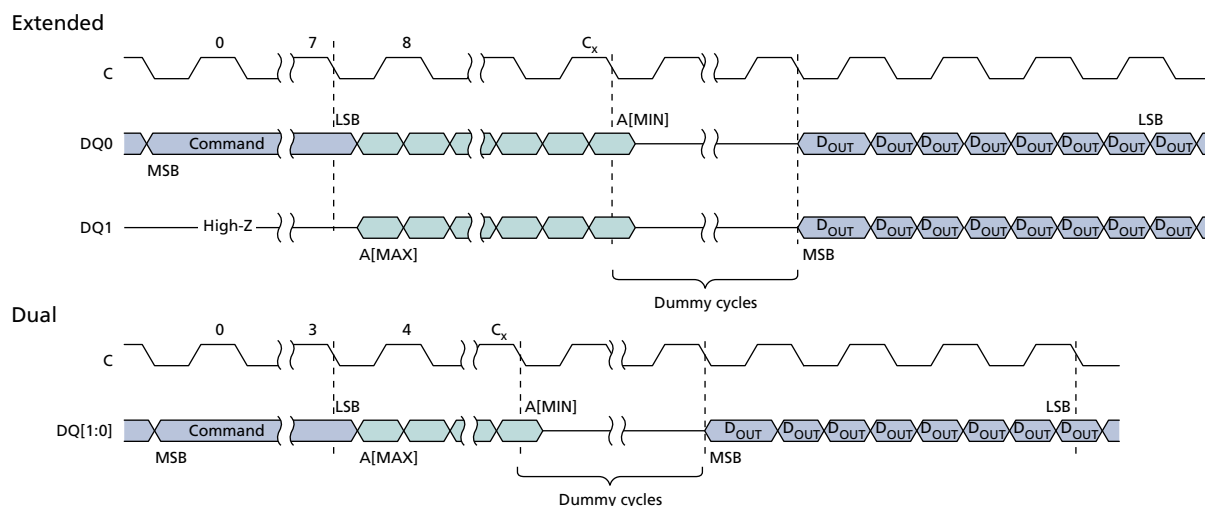
## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings

**Figure 20: DTR DUAL OUTPUT FAST READ – 3Dh<sup>3</sup>**



- Notes:
1. For extended protocol,  $C_x = 7 + (A[MAX] + 1)/2$ ; For dual protocol,  $C_x = 3 + (A[MAX] + 1)/4$ .
  2. S# not shown.
  3. DTR DUAL OUTPUT FAST READ and 4-BYTE DTR DUAL OUTPUT FAST READ commands.

**Figure 21: DTR DUAL INPUT/OUTPUT FAST READ – BDh<sup>3</sup>**



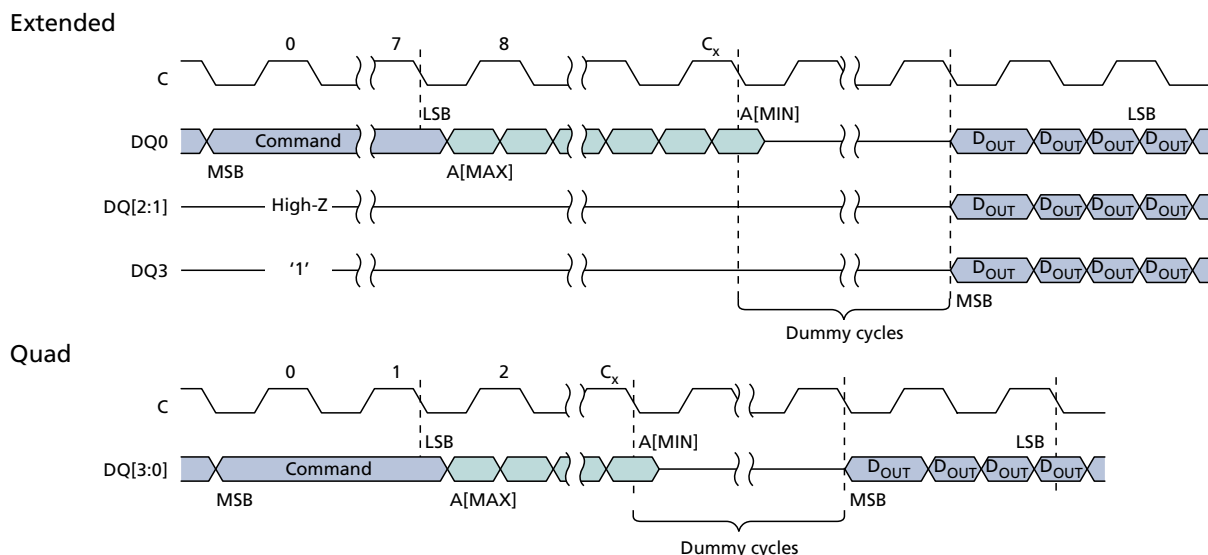
- Notes:
1. For extended protocol,  $C_x = 7 + (A[MAX] + 1)/4$ ; For dual protocol,  $C_x = 3 + (A[MAX] + 1)/8$ .
  2. S# not shown.
  3. DTR DUAL INPUT/OUTPUT FAST READ and 4-BYTE DTR DUAL INPUT/OUTPUT FAST READ commands.





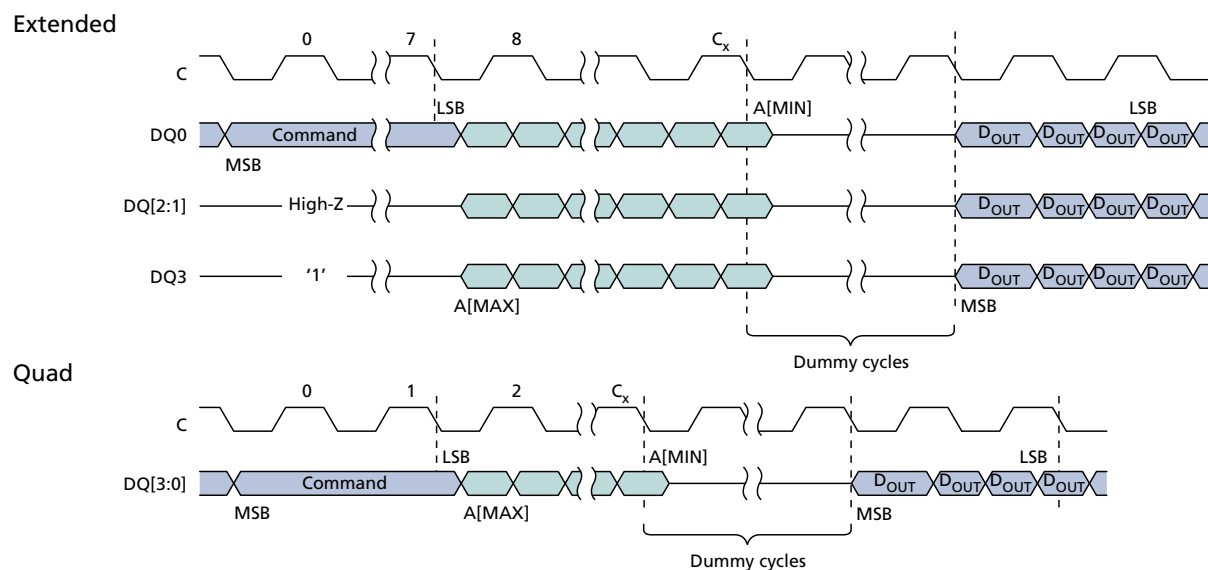
## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings

**Figure 22: DTR QUAD OUTPUT FAST READ – 6Dh<sup>3</sup>**



- Notes:
1. For extended protocol,  $C_x = 7 + (A[MAX] + 1)/2$ ; For quad protocol,  $C_x = 1 + (A[MAX] + 1)/8$ .
  2. S# not shown.
  3. DTR QUAD OUTPUT FAST READ and 4-BYTE DTR QUAD OUTPUT FAST READ commands.

**Figure 23: DTR QUAD INPUT/OUTPUT FAST READ – EDh<sup>3</sup>**



- Notes:
1. For extended protocol,  $C_x = 7 + (A[MAX] + 1)/8$ ; For quad protocol,  $C_x = 1 + (A[MAX] + 1)/8$ .
  2. S# not shown.



## **512Mb, 1.8V Multiple I/O Serial Flash Memory READ MEMORY Operations Timings**

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3. DTR QUAD INPUT/OUTPUT FAST READ and 4-BYTE DTR QUAD INPUT/OUTPUT FAST READ commands.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory WRITE ENABLE/DISABLE Operations

### WRITE ENABLE/DISABLE Operations

To initiate a command, S# is driven LOW and held LOW until the eighth bit of the command code has been latched in, after which it must be driven HIGH. For extended, dual, and quad SPI protocols respectively, the command code is input on DQ0, DQ[1:0], and DQ[3:0]. If S# is not driven HIGH after the command code has been latched in, the command is not executed, flag status register error bits are not set, and the write enable latch remains cleared to its default setting of 0, providing protection against errant data modification.

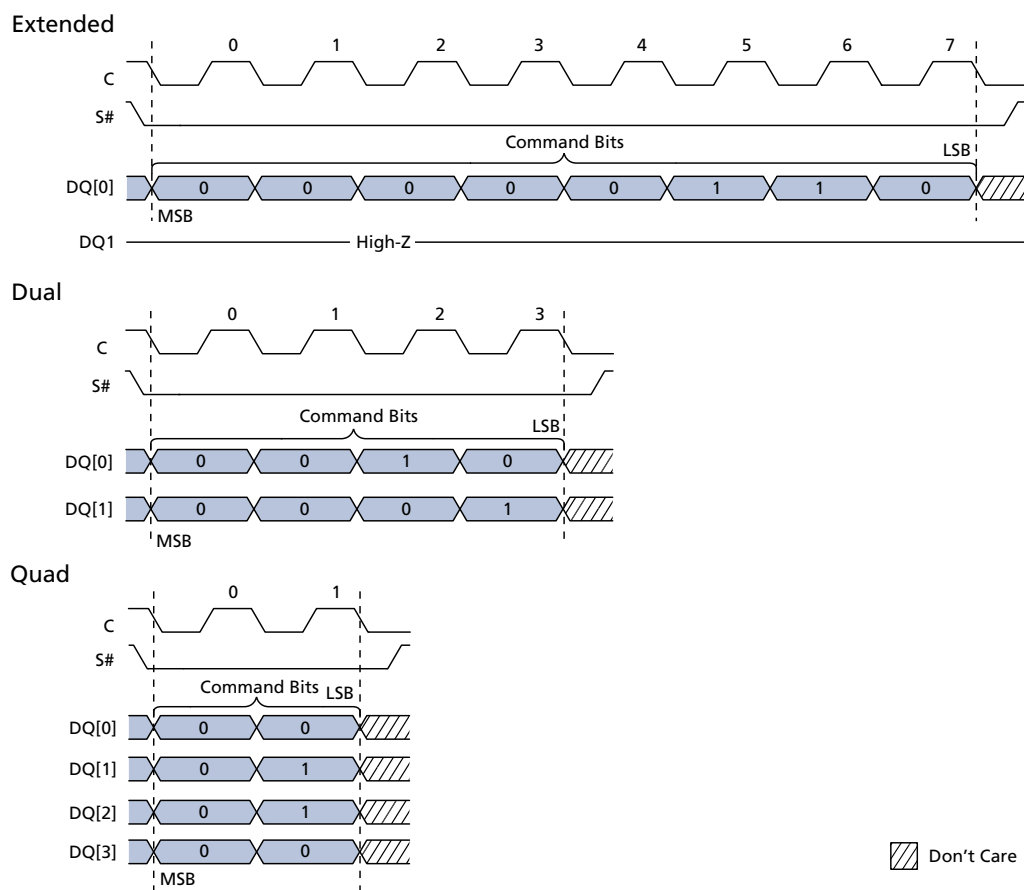
**Table 26: WRITE ENABLE/DISABLE Operations**

Operation Name	Description/Conditions
WRITE ENABLE	Sets the write enable latch bit before each PROGRAM, ERASE, and WRITE command.
WRITE DISABLE	Clears the write enable latch bit. In case of a protection error, WRITE DISABLE will not clear the bit. Instead, a CLEAR FLAG STATUS REGISTER command must be issued to clear both flags.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory WRITE ENABLE/DISABLE Operations

**Figure 24: WRITE ENABLE and WRITE DISABLE Timing**



Note: 1. WRITE ENABLE command sequence and code, shown here, is 06h (0000 0110 binary);  
WRITE DISABLE is identical, but its command code is 04h (0000 0100 binary).



## 512Mb, 1.8V Multiple I/O Serial Flash Memory READ REGISTER Operations

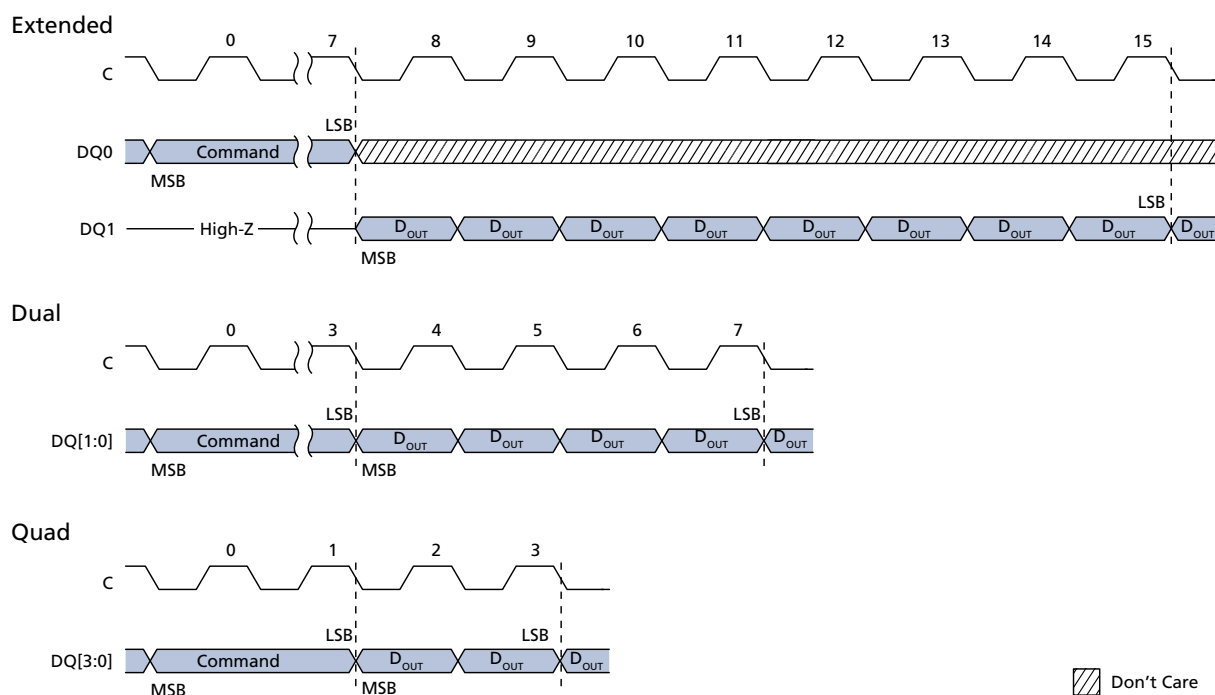
### READ REGISTER Operations

To initiate a command, S# is driven LOW. For extended SPI protocol, input is on DQ0, output on DQ1. For dual SPI protocol, input/output is on DQ[1:0] and for quad SPI protocol, input/output is on DQ[3:0]. The operation is terminated by driving S# HIGH at any time during data output.

**Table 27: READ REGISTER Operations**

Operation Name	Description/Conditions
READ STATUS REGISTER (05h)	Can be read continuously and at any time, including during a PROGRAM, ERASE, or WRITE operation. If one of these operations is in progress, checking the write in progress bit or P/E controller bit is recommended before executing the command.
READ FLAG STATUS REGISTER (70h)	
READ NONVOLATILE CONFIGURATION REGISTER (B5h)	Can be read continuously. After all 16 bits of the register have been read, a 0 is output. All reserved fields output a value of 1.
READ VOLATILE CONFIGURATION REGISTER (85h)	When the register is read continuously, the same byte is output repeatedly.
READ ENHANCED VOLATILE CONFIGURATION REGISTER (65h)	
READ EXTENDED ADDRESS REGISTER (C8h)	

**Figure 25: READ REGISTER Timing**



- Notes:
1. Supports all READ REGISTER commands except DYNAMIC PROTECTION BITS READ.
  2. A READ NONVOLATILE CONFIGURATION REGISTER operation will output data starting from the least significant byte.
  3. S# not shown.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory WRITE REGISTER Operations

### WRITE REGISTER Operations

Before a WRITE REGISTER command is initiated, the WRITE ENABLE command must be executed to set the write enable latch bit to 1. To initiate a command, S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH; for the WRITE NONVOLATILE CONFIGURATION REGISTER command, S# is held LOW until the 16th bit of the last data byte has been latched in. For the extended, dual, and quad SPI protocols respectively, input is on DQ0, DQ[1:0], and DQ[3:0], followed by the data bytes. If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. The operation is self-timed and its duration is  $t_W$  for WRITE STATUS REGISTER and  $t_{NVCR}$  for WRITE NONVOLATILE CONFIGURATION REGISTER.

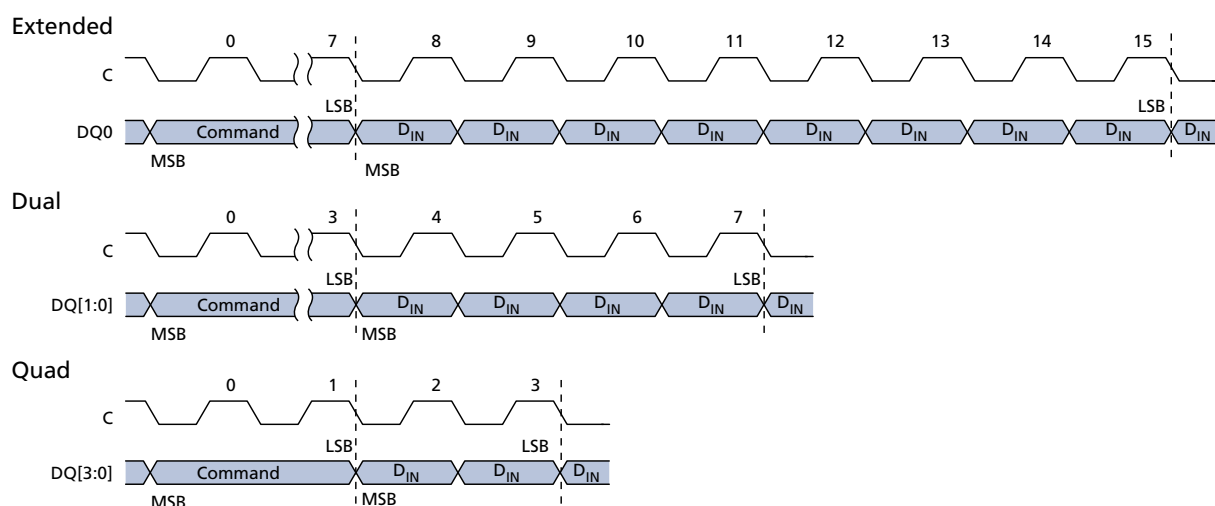
**Table 28: WRITE REGISTER Operations**

Operation Name	Description/Conditions
WRITE STATUS REGISTER (01h)	The WRITE STATUS REGISTER command writes new values to status register bits 7:2, enabling software data protection. The status register can also be combined with the W# signal to provide hardware data protection. This command has no effect on status register bits 1:0.
WRITE NONVOLATILE CONFIGURATION REGISTER (B1h)	For the WRITE STATUS REGISTER and WRITE NONVOLATILE CONFIGURATION REGISTER commands, when the operation is in progress, the write in progress bit is set to 1. The write enable latch bit is cleared to 0, whether the operation is successful or not. The status register and flag status register can be polled for the operation status. When the operation completes, the write in progress bit is cleared to 0, whether the operation is successful or not.
WRITE VOLATILE CONFIGURATION REGISTER (81h)	Because register bits are volatile, change to the bits is immediate. Reserved bits are not affected by this command.
WRITE ENHANCED VOLATILE CONFIGURATION REGISTER (61h)	
WRITE EXTENDED ADDRESS REGISTER (C5h)	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory WRITE REGISTER Operations

**Figure 26: WRITE REGISTER Timing**



- Notes:
1. Supports all WRITE REGISTER commands except WRITE LOCK REGISTER.
  2. A WRITE NONVOLATILE CONFIGURATION REGISTER operation requires data being sent starting from least significant byte.
  3. S# not shown.



# 512Mb, 1.8V Multiple I/O Serial Flash Memory CLEAR FLAG STATUS REGISTER Operation

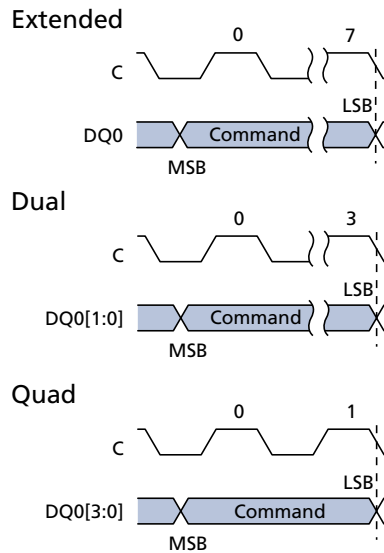
## CLEAR FLAG STATUS REGISTER Operation

To initiate a command, S# is driven LOW. For the extended, dual, and quad SPI protocols respectively, input is on DQ0, DQ[1:0], and DQ[3:0]. The operation is terminated by driving S# HIGH at any time.

**Table 29: CLEAR FLAG STATUS REGISTER Operation**

Operation Name	Description/Conditions
CLEAR FLAG STATUS REGISTER (50h)	Resets the error bits (erase, program, and protection)

**Figure 27: CLEAR FLAG STATUS REGISTER Timing**



Note: 1. S# not shown.





## 512Mb, 1.8V Multiple I/O Serial Flash Memory PROGRAM Operations

### PROGRAM Operations

Before a PROGRAM command is initiated, the WRITE ENABLE command must be executed to set the write enable latch bit to 1. To initiate a command, S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH. If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. Each address bit is latched in during the rising edge of the clock. When a command is applied to a protected sector, the command is not executed, the write enable latch bit remains set to 1, and flag status register bits 1 and 4 are set. If the operation times out, the write enable latch bit is reset and the program fail bit is set to 1.

**Note:** The manner of latching data shown and explained in the timing diagrams ensures that the number of clock pulses is a multiple of one byte before command execution, helping reduce the effects of noisy or undesirable signals and enhancing device data protection.

**Table 30: PROGRAM Operations**

Operation Name	Description/Conditions
PAGE PROGRAM (02h)	A PROGRAM operation changes a bit from 1 to 0.
DUAL INPUT FAST PROGRAM (A2h)	When the operation is in progress, the write in progress bit is set to 1.
EXTENDED DUAL INPUT FAST PROGRAM (D2h)	The write enable latch bit is cleared to 0, whether the operation is successful or not. The status register and flag status register can be polled for the operation status. When the operation completes, the write in progress bit is cleared to 0. An operation can be paused or resumed by the PROGRAM/ERASE SUSPEND or PROGRAM/ERASE RESUME command, respectively.
QUAD INPUT FAST PROGRAM (32h)	
EXTENDED QUAD INPUT FAST PROGRAM (38h)	If the bits of the least significant address, which is the starting address, are not all zero, all data transmitted beyond the end of the current page is programmed from the starting address of the same page. If the number of bytes sent to the device exceed the maximum page size, previously latched data is discarded and only the last maximum page-size number of data bytes are guaranteed to be programmed correctly within the same page. If the number of bytes sent to the device is less than the maximum page size, they are correctly programmed at the specified addresses without any effect on the other bytes of the same page.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory 4-BYTE PROGRAM Operations

### 4-BYTE PROGRAM Operations

**Table 31: 4-BYTE PROGRAM Operations**

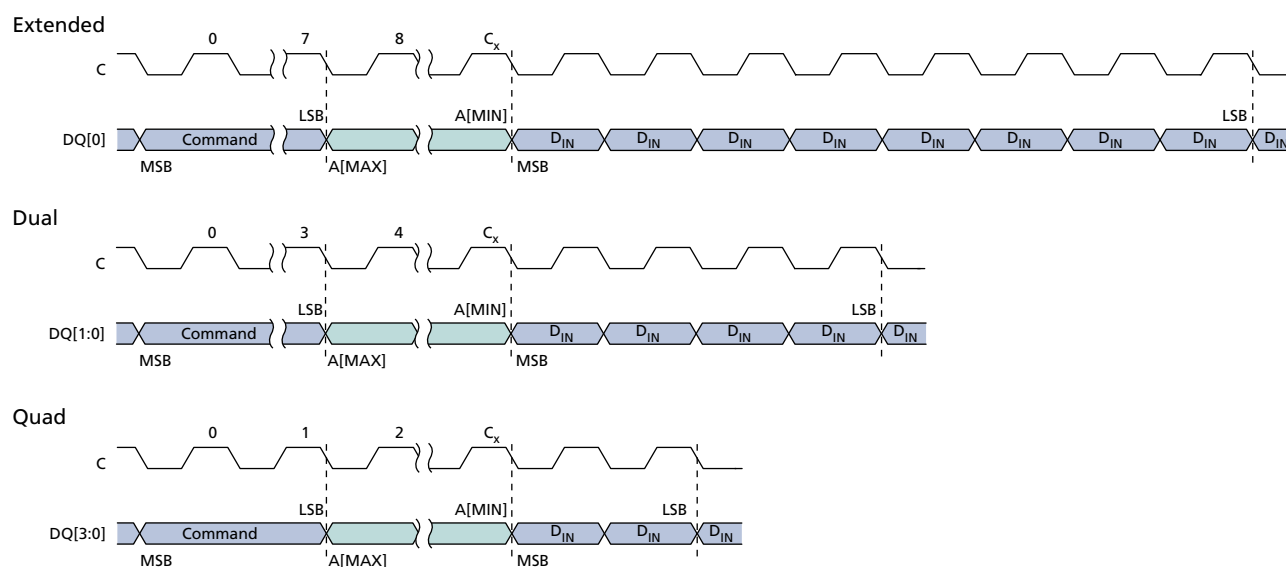
Operation Name	Description/Conditions
4-BYTE PAGE PROGRAM (12h)	PROGRAM operations can be extended to a 4-bytes address range, with [A31:0] input during address cycle.  Selection of the 3-byte or 4-byte address range can be enabled in two ways: through the nonvolatile configuration register or through the ENABLE 4-BYTE ADDRESS MODE/EXIT 4-BYTE ADDRESS MODE commands. 4-BYTE commands and DTR 4-BYTE commands function in 4-BYTE and DTR 4-BYTE mode regardless of settings in the nonvolatile configuration register or enhanced volatile configuration register; other commands function in 4-BYTE and DTR modes only after the mode is enabled by the register settings.
4-BYTE QUAD INPUT FAST PROGRAM (34h)	
4-BYTE EXTENDED QUAD INPUT FAST PROGRAM (3Eh)	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory PROGRAM Operations Timings

### PROGRAM Operations Timings

**Figure 28: PAGE PROGRAM Command**

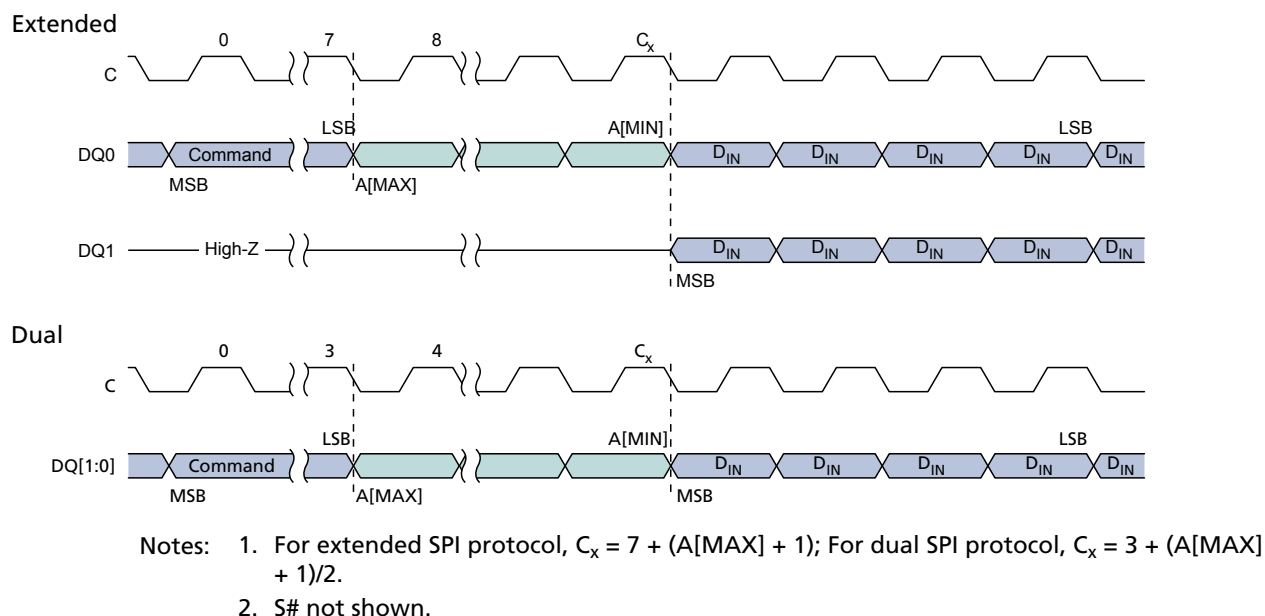


- Notes:
1. For extended SPI protocol,  $C_x = 7 + (A[\text{MAX}] + 1)$ ; For dual SPI protocol,  $C_x = 3 + (A[\text{MAX}] + 1)/2$ ; For quad SPI protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .
  2. S# not shown. The operation is self-timed, and its duration is  $t_{\text{PP}}$ .

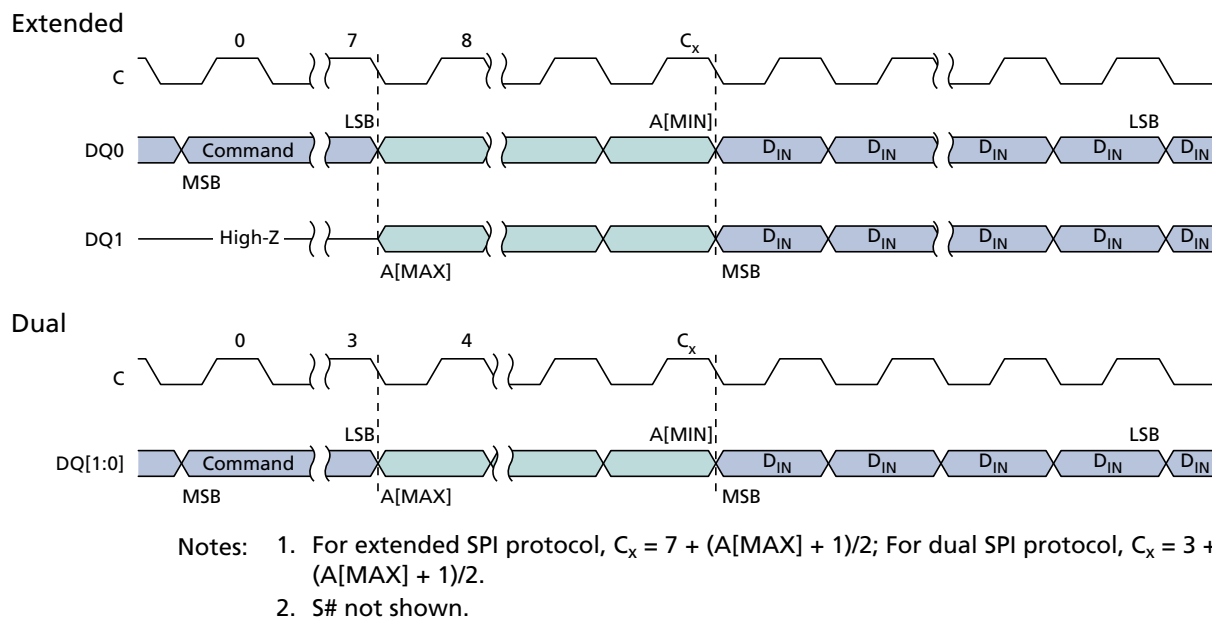


## 512Mb, 1.8V Multiple I/O Serial Flash Memory PROGRAM Operations Timings

**Figure 29: DUAL INPUT FAST PROGRAM Command**



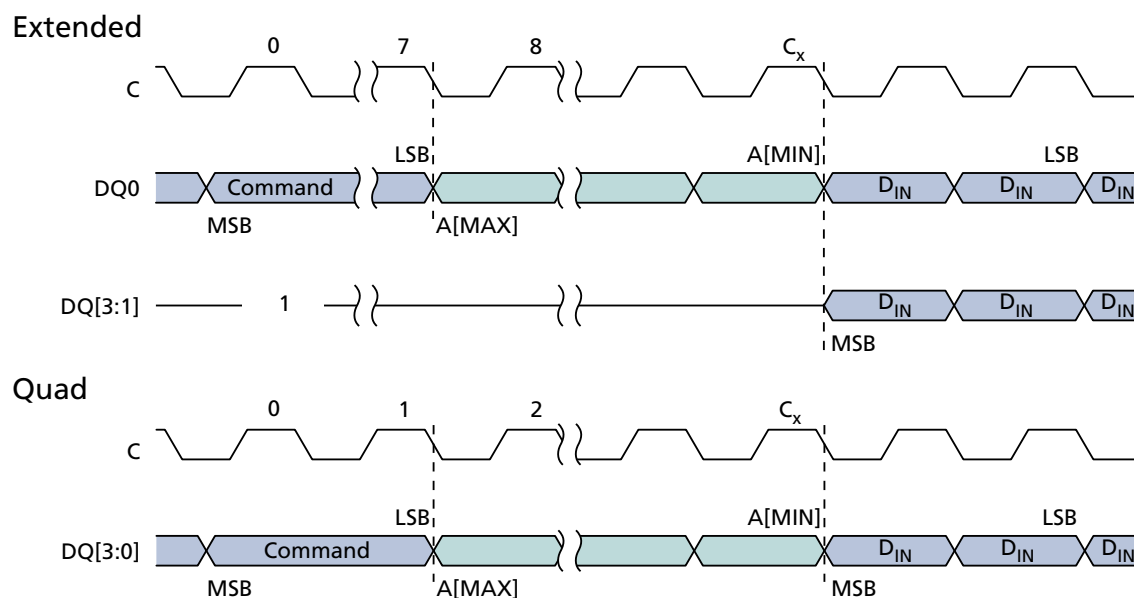
**Figure 30: EXTENDED DUAL INPUT FAST PROGRAM Command**





## 512Mb, 1.8V Multiple I/O Serial Flash Memory PROGRAM Operations Timings

**Figure 31: QUAD INPUT FAST PROGRAM Command**

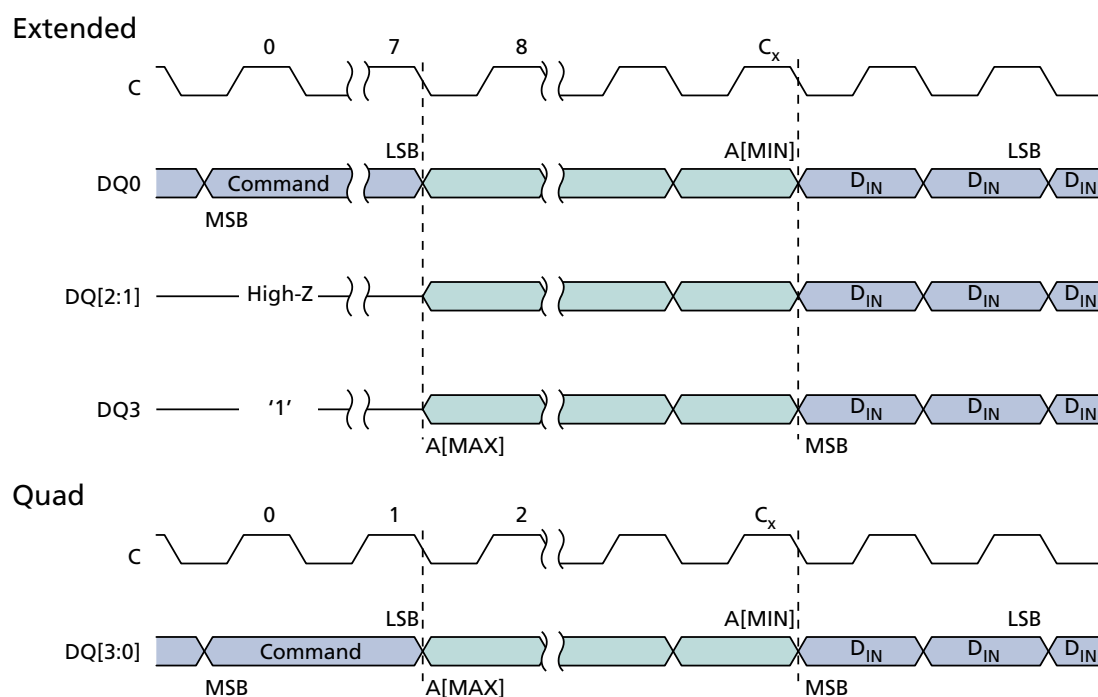


- Notes:
1. For extended SPI protocol,  $C_x = 7 + (A[\text{MAX}] + 1)/4$ ; For quad SPI protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .
  2. S# not shown.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory PROGRAM Operations Timings

**Figure 32: EXTENDED QUAD INPUT FAST PROGRAM Command**



- Notes:
1. For extended SPI protocol,  $C_x = 7 + (A[MAX] + 1)/4$ ; For quad SPI protocol,  $C_x = 1 + (A[MAX] + 1)/4$ .
  2. S# not shown.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory ERASE Operations

### ERASE Operations

An ERASE operation changes a bit from 0 to 1. Before any ERASE command is initiated, the WRITE ENABLE command must be executed to set the write enable latch bit to 1; if not, the device ignores the command and no error bits are set to indicate operation failure. S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH. The operations are self-timed, and duration is <sup>t</sup>SSE, <sup>t</sup>SE, or <sup>t</sup>BE according to command.

If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. A command applied to a protected subsector is not executed. Instead, the write enable latch bit remains set to 1, and flag status register bits 1 and 5 are set.

When the operation is in progress, the program or erase controller bit of the flag status register is set to 0. In addition, the write in progress bit is set to 1. When the operation completes, the write in progress bit is cleared to 0. The write enable latch bit is cleared to 0, whether the operation is successful or not. If the operation times out, the write enable latch bit is reset and the erase error bit is set to 1.

The status register and flag status register can be polled for the operation status. When the operation completes, these register bits are cleared to 1.

**Note:** For all ERASE operations, noisy or undesirable signal effects can be reduced and device data protection enhanced by holding S# LOW until the eighth bit of the last data byte has been latched in; this ensures that the number of clock pulses is a multiple of one byte before command execution.

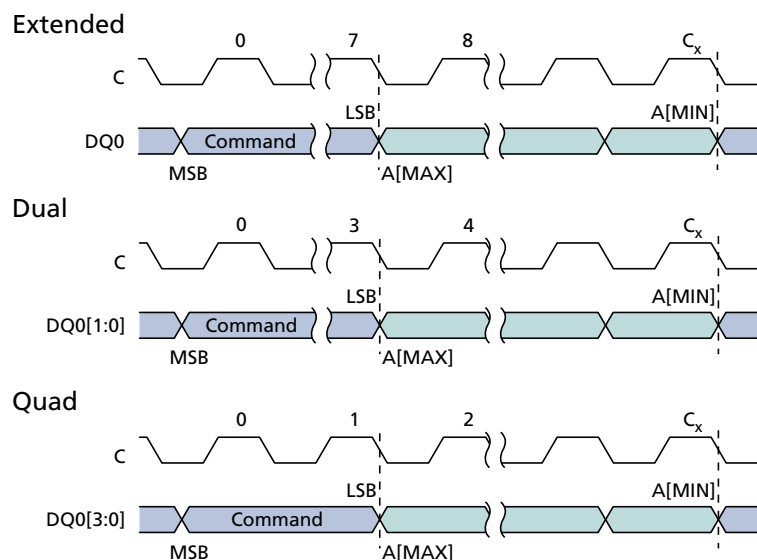
**Table 32: ERASE Operations**

Operation Name	Description/Conditions
SUBSECTOR ERASE	Sets the selected subsector or sector bits to FFh. Any address within the subsector is valid for entry. Each address bit is latched in during the rising edge of the clock. The operation can be suspended and resumed by the PROGRAM/ERASE SUSPEND and PROGRAM/ERASE RESUME commands, respectively.
SECTOR ERASE	
BULK ERASE	Sets the device bits to FFh. The command is not executed if any sector is locked. Instead, the write enable latch bit remains set to 1, and flag status register bits 1 and 5 are set.



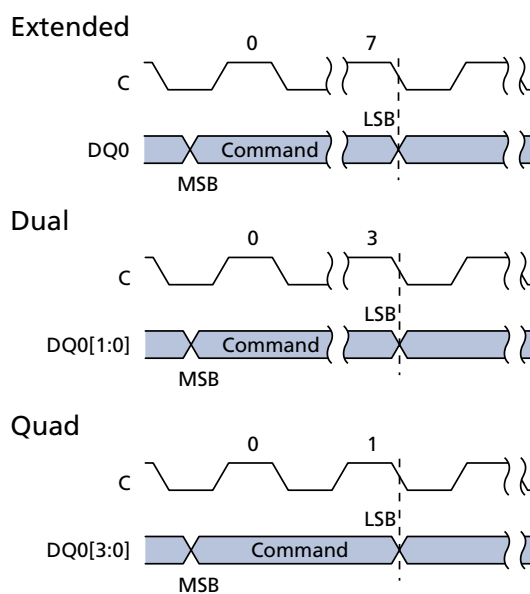
## 512Mb, 1.8V Multiple I/O Serial Flash Memory ERASE Operations

**Figure 33: SUBSECTOR and SECTOR ERASE Timing**



- Notes:
1. For extended SPI protocol,  $C_x = 7 + (A[\text{MAX}] + 1)$ ; For dual SPI protocol,  $C_x = 3 + (A[\text{MAX}] + 1)/2$ ; For quad SPI protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .
  2. S# not shown.

**Figure 34: BULK ERASE Timing**



- Note:
1. S# not shown.





## 512Mb, 1.8V Multiple I/O Serial Flash Memory SUSPEND/RESUME Operations

### SUSPEND/RESUME Operations

#### PROGRAM/ERASE SUSPEND Operations

A PROGRAM/ERASE SUSPEND command enables the memory controller to interrupt and suspend an array PROGRAM or ERASE operation within the program/erase latency. To initiate the command, S# is driven LOW, and the command code is input on DQn. The operation is terminated by the PROGRAM/ERASE RESUME command.

For a PROGRAM SUSPEND, the flag status register bit 2 is set to 1. For an ERASE SUSPEND, the flag status register bit 6 is set to 1.

After an erase/program latency time, the flag status register bit 7 is also set to 1, but the device is considered in suspended state once bit 7 of the flag status register outputs 1 with at least one byte output. In the suspended state, the device is waiting for any operation.

If the time remaining to complete the operation is less than the suspend latency, the device completes the operation and clears the flag status register bits 2 or 6, as applicable. Because the suspend state is volatile, if there is a power cycle, the suspend state information is lost and the flag status register powers up as 80h.

It is possible to nest a PROGRAM/ERASE SUSPEND operation inside a PROGRAM/ERASE SUSPEND operation just once. Issue an ERASE command and suspend it. Then issue a PROGRAM command and suspend it also. With the two operations suspended, the next PROGRAM/ERASE RESUME command resumes the latter operation, and a second PROGRAM/ERASE RESUME command resumes the former (or first) operation.

#### PROGRAM/ERASE RESUME Operations

A PROGRAM/ERASE RESUME operation terminates the PROGRAM/ERASE RESUME command. To initiate the command, S# is driven LOW, and the command code is input on DQn. The operation is terminated by driving S# HIGH.

**Table 33: SUSPEND/RESUME Operations**

Operation Name	Description/Conditions
PROGRAM SUSPEND	A READ operation is possible in any page except the one in a suspended state. Reading from a page that is in a suspended state will output indeterminate data.
ERASE SUSPEND	A PROGRAM or READ operation is possible in any sector except the one in a suspended state. Reading from a sector that is in a suspended state will output indeterminate data. The device ignores a PROGRAM command to a sector that is in an erase suspend state; it also sets the flag status register bit 4 to 1, program failure/protection error, and leaves the write enable latch bit unchanged. When the ERASE resumes, it does not check the new lock status of the WRITE VOLATILE LOCK BITS command.



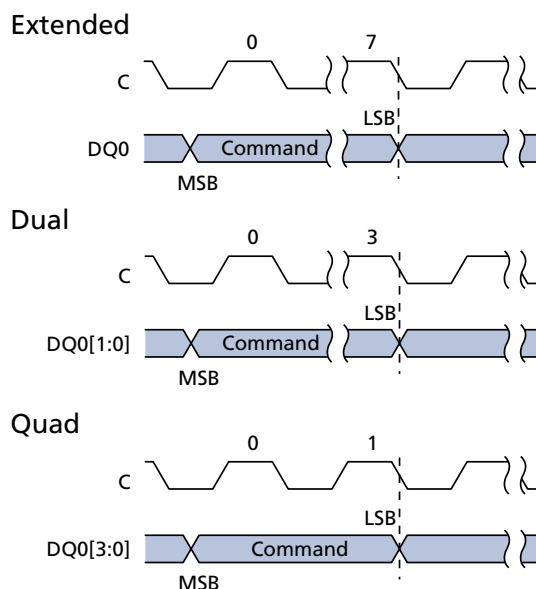
## 512Mb, 1.8V Multiple I/O Serial Flash Memory SUSPEND/RESUME Operations

**Table 33: SUSPEND/RESUME Operations (Continued)**

Operation Name	Description/Conditions
PROGRAM RESUME	<p>The status register write in progress bit is set to 1 and the flag status register program erase controller bit is set to 0. The command is ignored if the device is not in a suspended state.</p> <p>When the operation is in progress, the program or erase controller bit of the flag status register is set to 0. The flag status register can be polled for the operation status. When the operation completes, that bit is cleared to 1.</p>
ERASE RESUME	

Note: 1. See the Operations Allowed/Disallowed During Device States table.

**Figure 35: PROGRAM/ERASE SUSPEND or RESUME Timing**



Note: 1. S# not shown.



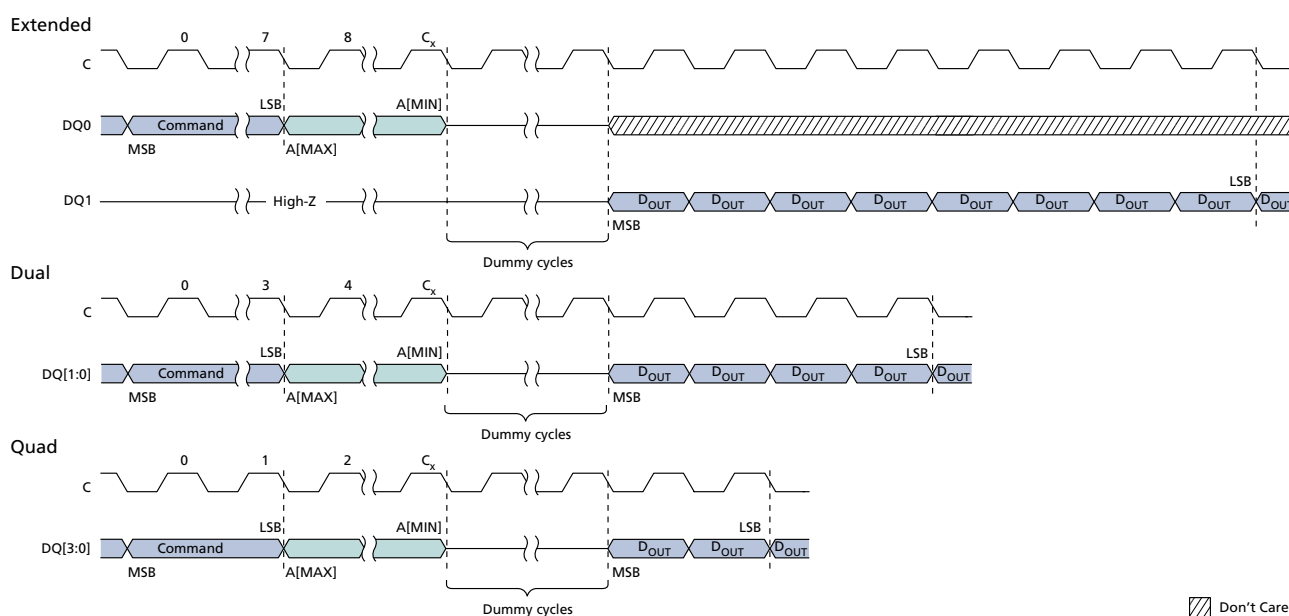
## 512Mb, 1.8V Multiple I/O Serial Flash Memory ONE-TIME PROGRAMMABLE Operations

### ONE-TIME PROGRAMMABLE Operations

#### READ OTP ARRAY Command

To initiate a READ OTP ARRAY command, S# is driven LOW. The command code is input on DQ0, followed by address bytes and dummy clock cycles. Each address bit is latched in during the rising edge of C. Data is shifted out on DQ1, beginning from the specified address and at a maximum frequency of  $f_C$  (MAX) on the falling edge of the clock. The address increments automatically to the next address after each byte of data is shifted out. There is no rollover mechanism; therefore, if read continuously, after location 0x40, the device continues to output data at location 0x40. The operation is terminated by driving S# HIGH at any time during data output.

Figure 36: READ OTP Command



Note: 1. For extended SPI protocol,  $C_x = 7 + (A[\text{MAX}] + 1)$ ; For dual SPI protocol,  $C_x = 3 + (A[\text{MAX}] + 1)/2$ ; For quad SPI protocol,  $C_x = 1 + (A[\text{MAX}] + 1)/4$ .

#### PROGRAM OTP ARRAY Command

To initiate the PROGRAM OTP ARRAY command, the WRITE ENABLE command must be issued to set the write enable latch bit to 1; otherwise, the PROGRAM OTP ARRAY command is ignored and flag status register bits are not set. S# is driven LOW and held LOW until the eighth bit of the last data byte has been latched in, after which it must be driven HIGH. The command code is input on DQ0, followed by address bytes and at least one data byte. Each address bit is latched in during the rising edge of the clock. When S# is driven HIGH, the operation, which is self-timed, is initiated; its duration is  $t_{\text{POTP}}$ . There is no rollover mechanism; therefore, after a maximum of 65 bytes are latched in the subsequent bytes are discarded.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory ONE-TIME PROGRAMMABLE Operations

PROGRAM OTP ARRAY programs, at most, 64 bytes to the OTP memory area and one OTP control byte. When the operation is in progress, the write in progress bit is set to 1. The write enable latch bit is cleared to 0, whether the operation is successful or not, and the status register and flag status register can be polled for the operation status. When the operation completes, the write in progress bit is cleared to 0.

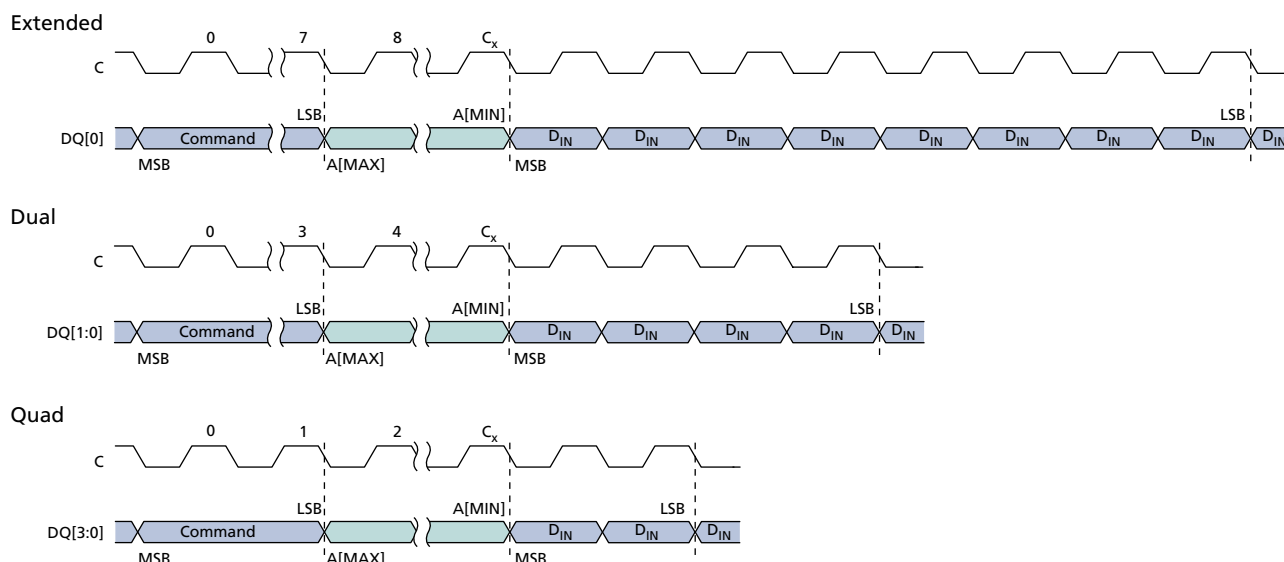
If the operation times out, the write enable latch bit is reset and the program fail bit is set to 1. If S# is not driven HIGH, the command is not executed, flag status register error bits are not set, and the write enable latch remains set to 1. The operation is considered complete once bit 7 of the flag status register outputs 1 with at least one byte output.

The OTP control byte (byte 64) is used to permanently lock the OTP memory array.

**Table 34: OTP Control Byte (Byte 64)**

Bit	Name	Settings	Description
0	OTP control byte	0 = Locked 1 = Unlocked (Default)	Used to permanently lock the 64-byte OTP array. When bit 0 = 1, the 64-byte OTP array can be programmed. When bit 0 = 0, the 64-byte OTP array is read only.  Once bit 0 has been programmed to 0, it can no longer be changed to 1. Program OTP array is ignored, the write enable latch bit remains set, and flag status register bits 1 and 4 are set.

**Figure 37: PROGRAM OTP Command**



Note: 1. For extended SPI protocol,  $C_x = 7 + (A[Max] + 1)$ ; For dual SPI protocol,  $C_x = 3 + (A[Max] + 1)/2$ ; For quad SPI protocol,  $C_x = 1 + (A[Max] + 1)/4$ .



## 512Mb, 1.8V Multiple I/O Serial Flash Memory ADDRESS MODE Operations

### ADDRESS MODE Operations

To initiate these commands, S# is driven LOW, and the command is be input on DQ<sub>n</sub>.

**Table 35: ENTER or EXIT 4-BYTE ADDRESS MODE Operations**

Operation Name	Description/Conditions
ENTER 4-BYTE ADDRESS MODE (B7h)	The effect of the command is immediate. The default address mode is three bytes, and the device returns to the default upon exiting the 4-byte address mode.
EXIT 4-BYTE ADDRESS MODE (E9h)	

### ENTER QUAD and RESET QUAD Operations

#### ENTER QUAD or RESET QUAD Command

To initiate these commands, the WRITE ENABLE command must not be executed. S# must be driven LOW, and the command must be input on DQ<sub>n</sub>.

**Table 36: ENTER or EXIT 4-BYTE ADDRESS MODE Operations**

Operation Name	Description/Conditions
ENTER QUAD (35h)	The effect of the command is immediate.
RESET QUAD (F5h)	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory CYCLIC REDUNDANCY CHECK Operations

### CYCLIC REDUNDANCY CHECK Operations

#### Cyclic Redundancy Check (CRC)

A cyclic redundancy check (CRC) is a non-secure hash function designed to detect accidental changes to raw data, and commonly used in digital networks and storage devices such as hard disk drives (the MT25Q CRC-64 operation follows the ECMA standard).

A CRC-enabled device calculates a short, fixed-length binary sequence, known as the CRC code or just CRC, for each block of data and sends or stores them.

When a block is read or received, the device repeats the calculation; if the new CRC does not match (or in some cases, cancel out) the one calculated earlier then the block contains a data error and the device may take corrective action such as rereading or re-requesting the block be sent again.

The device supports CRC operation initialized by an ACTIVATE INTERFACE operation, followed by the specific command code, which will generate the CRC result of the whole device or of an address range specified by the operation, then the CRC result will be compared with the expected CRC data provided in the sequence, and finally, the device will indicate a pass or fail through the status register.

The state of the write enable latch bit is "Don't Care" for the CYCLIC REDUNDANCY CHECK operation. In the case of a CRC operation on a range, the stop address must be equal to or greater than the start address; otherwise, the device will abort the operation with flag status register bit 1 set. The minimum granularity of the range is one byte.

If the CRC value generated by device does not match value provided by the user, error is indicated by setting flag status register bit 4. The CRC operation cannot be suspended. The user interface accepts a suspend request (immediately sets flag status register bit 2); however, the device ignores suspend request and completes the operation (at the end of the operation, flag status register bit 2 is cleared). The operation is aborted with hardware or software reset.

**Table 37: CRC Command Sequence on Entire Device**

Command Sequence		Description
Byte#	Data	
1	9Bh	Command code for interface activation
2	27h	Sub-command code for CRC operation
3	FFh	CRC operation option selection (CRC operation on entire device)
4	CRC[7:0]	1st byte of expected CRC value
5–10	CRC[55:8]	2nd to 7th byte of expected CRC value
11	CRC[63:56]	8th byte of expected CRC value
Drive S# HIGH		Operation sequence confirmed; CRC operation starts



## 512Mb, 1.8V Multiple I/O Serial Flash Memory CYCLIC REDUNDANCY CHECK Operations

**Table 38: CRC Command Sequence on a Range**

Command Sequence		Description
Byte#	Data	
1	9Bh	Command code for interface activation
2	27h	Sub-command code for CRC operation
3	FEh	CRC operation option selection (CRC operation on a range)
4	CRC[7:0]	1st byte of expected CRC value
5 to 10	CRC[55:8]	2nd to 7th byte of expected CRC value
11	CRC[63:56]	8th byte of expected CRC value
12	Start Address [7:0]	Specifies the starting byte address for CRC operation
13 to 14	Start Address [23:8]	
15	Start Address [31:24]	
16	Start Address [7:0]	Specifies the ending byte address for CRC operation
17 to 18	Start Address [23:8]	
19	Start Address [31:24]	
Drive S# HIGH		Operation sequence confirmed; CRC operation starts



## 512Mb, 1.8V Multiple I/O Serial Flash Memory State Table

### State Table

The device can be in only one state at a time. Depending on the state of the device, some operations as shown in the table below are allowed (Yes) and others are not (No). For example, when the device is in the standby state, all operations except SUSPEND are allowed in any sector. For all device states except the erase suspend state, if an operation is allowed or disallowed in one sector, it is allowed or disallowed in all other sectors. In the erase suspend state, a PROGRAM operation is allowed in any sector except the one in which an ERASE operation has been suspended.

**Table 39: Operations Allowed/Disallowed During Device States**

Operation	Standby State	Program or Erase State	Subsector Erase Suspend or Program Suspend State	Erase Suspend State	Notes
READ (memory)	Yes	No	Yes	Yes	1
READ (status/flag status registers)	Yes	Yes	Yes	Yes	6
PROGRAM	Yes	No	No	Yes/No	2
ERASE (sector/subsector)	Yes	No	No	No	3
WRITE	Yes	No	No	No	4
WRITE	Yes	No	Yes	Yes	5
SUSPEND	No	Yes	No	No	7

- Notes:
1. All READ operations except READ STATUS REGISTER and READ FLAG REGISTER. When issued to a sector or subsector that is simultaneously in an erase suspend state, the READ operation is accepted, but the data output is not guaranteed until the erase has completed.
  2. All PROGRAM operations except PROGRAM OTP. In the erase suspend state, a PROGRAM operation is allowed in any sector (Yes) except the sector (No) in which an ERASE operation has been suspended.
  3. Applies to the SECTOR ERASE or SUBSECTOR ERASE operation.
  4. Applies to the following operations: WRITE STATUS REGISTER, WRITE NONVOLATILE CONFIGURATION REGISTER, PROGRAM OTP, and BULK ERASE.
  5. Applies to the WRITE VOLATILE CONFIGURATION REGISTER, WRITE ENHANCED VOLATILE CONFIGURATION REGISTER, WRITE ENABLE, WRITE DISABLE, CLEAR FLAG STATUS REGISTER, WRITE EXTENDED ADDRESS REGISTER, or WRITE LOCK REGISTER operation.
  6. Applies to the READ STATUS REGISTER or READ FLAG STATUS REGISTER operation.
  7. Applies to the PROGRAM SUSPEND or ERASE SUSPEND operation.





## 512Mb, 1.8V Multiple I/O Serial Flash Memory XIP Mode

### XIP Mode

Execute-in-place (XIP) mode allows the memory to be read by sending an address to the device and then receiving the data on one, two, or four pins in parallel, depending on the customer requirements. XIP mode offers maximum flexibility to the application, saves instruction overhead, and reduces random access time.

### Activate or Terminate XIP Using Volatile Configuration Register

Applications that boot in SPI and must switch to XIP use the volatile configuration register. XIP provides faster memory READ operations by requiring only an address to execute, rather than a command code and an address.

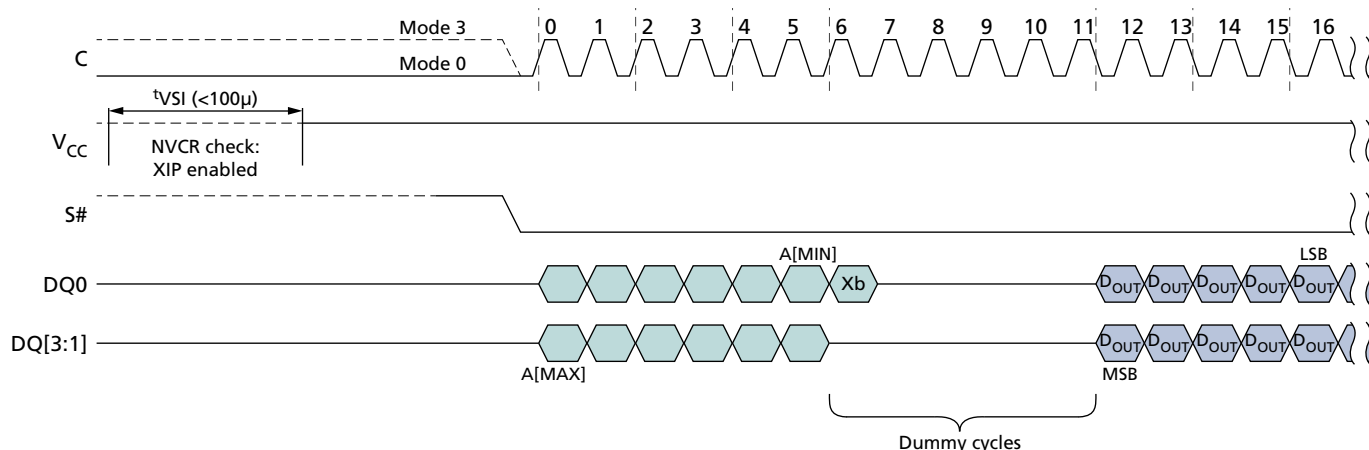
To activate XIP requires two steps. First, enable XIP by setting volatile configuration register bit 3 to 0. Next, drive the XIP confirmation bit to 0 during the next FAST READ operation. XIP is then active. Once in XIP, any command that occurs after S# is toggled requires only address bits to execute; a command code is not necessary, and device operations use the SPI protocol that is enabled. XIP is terminated by driving the XIP confirmation bit to 1. The device automatically resets volatile configuration register bit 3 to 1.

**Note:** For devices with basic XIP, indicated by a part number feature set digit of 2 or 4, it is not necessary to set the volatile configuration register bit 3 to 0 to enable XIP. Instead, it is enabled by setting the XIP confirmation bit to 0 during the first dummy clock cycle after any FAST READ command.

### Activate or Terminate XIP Using Nonvolatile Configuration Register

Applications that must boot directly in XIP use the nonvolatile configuration register. To enable a device to power-up in XIP using the nonvolatile configuration register, set non-volatile configuration register bits [11:9]. Settings vary according to protocol, as explained in the Nonvolatile Configuration Register section. Because the device boots directly in XIP, after the power cycle, no command code is necessary. XIP is terminated by driving the XIP confirmation bit to 1.

**Figure 38: XIP Mode Directly After Power-On**





## 512Mb, 1.8V Multiple I/O Serial Flash Memory XIP Mode

Note: 1. Xb is the XIP confirmation bit and should be set as follows: 0 to keep XIP state; 1 to exit XIP mode and return to standard read mode.

### Confirmation Bit Settings Required to Activate or Terminate XIP

The XIP confirmation bit setting activates or terminates XIP after it has been enabled or disabled. This bit is the value on DQ0 during the first dummy clock cycle in the FAST READ operation. In dual I/O XIP mode, the value of DQ1 during the first dummy clock cycle after the addresses is always "Don't Care." In quad I/O XIP mode, the values of DQ3, DQ2, and DQ1 during the first dummy clock cycle after the addresses are always "Don't Care."

**Table 40: XIP Confirmation Bit**

Bit Value	Description
0	Activates XIP: While this bit is 0, XIP remains activated.
1	Terminates XIP: When this bit is set to 1, XIP is terminated and the device returns to SPI.

**Table 41: Effects of Running XIP in Different Protocols**

Protocol	Effect
Extended I/O and Dual I/O	In a device with a dedicated part number where RST# is enabled, a LOW pulse on that pin resets XIP and the device to the state it was in previous to the last power-up, as defined by the nonvolatile configuration register.
Dual I/O	Values of DQ1 during the first dummy clock cycle are "Don't Care."
Quad I/O <sup>1</sup>	Values of DQ[3:1] during the first dummy clock cycle are "Don't Care." In a device with a dedicated part number, it is only possible to reset memory when the device is deselected.

Note: 1. In a device with a dedicated part number where RST# is enabled, a LOW pulse on that pin resets XIP and the device to the state it was in previous to the last power-up, as defined by the nonvolatile configuration register only when the device is deselected.

### Terminating XIP After a Controller and Memory Reset

The system controller and the device can become out of synchronization if, during the life of the application, the system controller is reset without the device being reset. In such a case, the controller can reset the memory to power-on reset if the memory has reset functionality. (Reset is available in devices with a dedicated part number.)

- 7 clock cycles within S# LOW (S# becomes HIGH before 8th clock cycle)
- + 9 clock cycles within S# LOW (S# becomes HIGH before 10th clock cycle)
- + 13 clock cycles within S# LOW (S# becomes HIGH before 14th clock cycle)
- + 17 clock cycles within S# LOW (S# becomes HIGH before 18th clock cycle)
- + 25 clock cycles within S# LOW (S# becomes HIGH before 26th clock cycle)
- + 33 clock cycles within S# LOW (S# becomes HIGH before 34th clock cycle)



## 512Mb, 1.8V Multiple I/O Serial Flash Memory XIP Mode

These sequences cause the controller to set the XIP confirmation bit to 1, thereby terminating XIP. However, it does not reset the device or interrupt PROGRAM/ERASE operations that may be in progress. After terminating XIP, the controller must execute RESET ENABLE and RESET MEMORY to implement a software reset and reset the device.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Power-Up and Power-Down

### Power-Up and Power-Down

#### Power-Up and Power-Down Requirements

At power-up and power-down, the device must not be selected; that is, S# must follow the voltage applied on  $V_{CC}$  until  $V_{CC}$  reaches the correct values:  $V_{CC,min}$  at power-up and  $V_{SS}$  at power-down.

To provide device protection and prevent data corruption and inadvertent WRITE operations during power-up, a power-on reset circuit is included. The logic inside the device is held to RESET while  $V_{CC}$  is less than the power-on reset threshold voltage shown here; all operations are disabled, and the device does not respond to any instruction. During a standard power-up phase, the device ignores all commands except READ STATUS REGISTER and READ FLAG STATUS REGISTER. These operations can be used to check the memory internal state. After power-up, the device is in standby power mode; the write enable latch bit is reset; the write in progress bit is reset; and the dynamic protection register is configured as: (write lock bit, lock down bit) = (0,0).

Normal precautions must be taken for supply line decoupling to stabilize the  $V_{CC}$  supply. Each device in a system should have the  $V_{CC}$  line decoupled by a suitable capacitor (typically 100nF) close to the package pins. At power-down, when  $V_{CC}$  drops from the operating voltage to below the power-on-reset threshold voltage shown here, all operations are disabled and the device does not respond to any command.

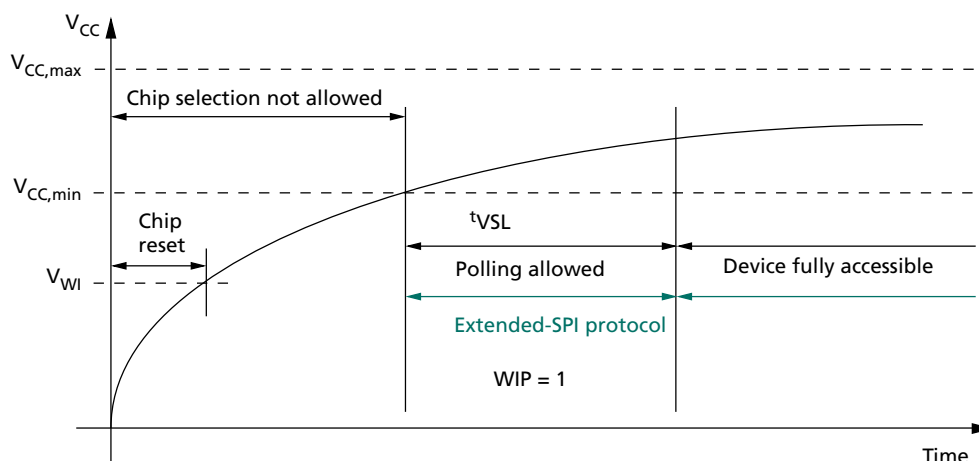
When the operation is in progress, the program or erase controller bit of the status register is set to 0. To obtain the operation status, the flag status register must be polled. When the operation completes, the program or erase controller bit is cleared to 1. The cycle is complete after the flag status register outputs the program or erase controller bit to 1.

**Note:** If power-down occurs while a WRITE, PROGRAM, or ERASE cycle is in progress, data corruption may result.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Power-Up and Power-Down

**Figure 39: Power-Up Timing**



- Notes:
1.  $t_{VSL}$  polling has to be in Extended-SPI protocol and STR mode.
  2. During  $t_{VSL}$  period,  $HOLD\#$  is enabled,  $RESET\#$  disabled, and output strength is in default setting.
  3. In a system that uses a fast  $V_{CC}$  ramp rate, current design requires a minimum 100 $\mu s$  after  $V_{CC}$  reaches  $V_{WI}$ , and before the polling is allowed, even though  $V_{CC,min}$  is achieved.

**Table 42: Power-Up Timing and  $V_{WI}$  Threshold**

Note 1 applies to entire table

Symbol	Parameter	Min	Max	Unit	Notes
$t_{VSL}$	$V_{CC,min}$ to device fully accessible	–	300	$\mu s$	2
$V_{WI}$	Write inhibit voltage	1.5	2.5	V	2

- Notes:
1. When  $V_{CC}$  reaches  $V_{CC,min}$ , user is allowed to poll SR in Extended-SPI protocol. The WIP bit must read as 1 while power-up initialization is in progress. When the initialization is complete and the user has full access to the device, the WIP bit must read as 0. At a point before the initialization is complete, the device configures the SPI protocol, as defined by the nonvolatile configuration register. This polling SR method for determining when the device is ready is only useful in Extended-SPI mode. If user enables DIO-SPI or QIO-SPI via the nonvolatile configuration register, it is recommended the user waits out the  $t_{VSL}$  time before accessing the device.
  2. Parameters listed are characterized only.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Power Loss and Interface Rescue

### Power Loss and Interface Rescue

If a power loss occurs during a WRITE NONVOLATILE CONFIGURATION REGISTER command, after the next power-on, the device might begin in an undetermined state (XIP mode or an unnecessary protocol). If this occurs, a power loss recovery sequence must reset the device to a fixed state (extended SPI protocol without XIP) until the next power-up.

If the controller and memory device get out of synchronization, the controller can follow an interface rescue sequence to reset the memory device interface to power-up to the last reset state (as defined by latest nonvolatile configuration register). This resets only the interface, not the entire memory device, and any ongoing operations are not interrupted.

After each sequence, the issue should be resolved definitively by running the WRITE NONVOLATILE CONFIGURATION REGISTER command again.

**Note:** The two steps in each sequence must be in the correct order, and  $t_{\text{SHSL2}}$  must be at least 50ns for the duration of each sequence.

The first step for both the power loss recovery and interface rescue sequences is described under "Recovery." The second step in the power loss recovery sequence is under "Power Loss Recovery" and the second step in the interface rescue sequence is under "Interface Rescue."

### Recovery

Step one of both the power loss recovery and interface rescue sequences is DQ0 (PAD DATA) and DQ3 (PAD HOLD) equal to 1 for the situations listed here:

- 7 clock cycles within S# LOW (S# becomes HIGH before 8th clock cycle)
- + 9 clock cycles within S# LOW (S# becomes HIGH before 10th clock cycle)
- + 13 clock cycles within S# LOW (S# becomes HIGH before 14th clock cycle)
- + 17 clock cycles within S# LOW (S# becomes HIGH before 18th clock cycle)
- + 25 clock cycles within S# LOW (S# becomes HIGH before 26th clock cycle)
- + 33 clock cycles within S# LOW (S# becomes HIGH before 34th clock cycle)

### Power Loss Recovery

For power loss recovery, the second part of the sequence is exiting from dual or quad SPI protocol by using the following FFh sequence: DQ0 and DQ3 equal to 1 for 8 clock cycles within S# LOW; S# becomes HIGH before 9th clock cycle. After this two-part sequence the extended SPI protocol is active.

### Interface Rescue

For interface rescue, the second part of the sequence is for exiting from dual or quad SPI protocol by using the following FFh sequence: DQ0 and DQ3 equal to 1 for 16 clock cycles within S# LOW; S# becomes HIGH before 17th clock cycle. For DTR protocol, 1 should be driven on both edges of clock for 16 cycles with S# LOW. After this two-part sequence, the extended SPI protocol is active.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Absolute Ratings and Operating Conditions

### Absolute Ratings and Operating Conditions

Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only. Exposure to absolute maximum rating for extended periods may adversely affect reliability. Stressing the device beyond the absolute maximum ratings may cause permanent damage.

**Table 43: Absolute Ratings**

Symbol	Parameter	Min	Max	Units	Notes
$T_{STG}$	Storage temperature	-65	150	°C	
$T_{LEAD}$	Lead temperature during soldering	–	See note 1	°C	
$V_{CC}$	Supply voltage	-0.6	4.0	V	2
$V_{IO}$	Input/output voltage with respect to ground	2	$V_{CC} + 2$	V	2
$V_{ESD}$	Electrostatic discharge voltage (human body model)	-2000	2000	V	2, 3

- Notes:
1. Compliant with JEDEC Standard J-STD-020C (for small-body, Sn-Pb or Pb assembly), RoHS, and the European directive on Restrictions on Hazardous Substances (RoHS) 2002/95/EU.
  2. All specified voltages are with respect to  $V_{SS}$ . During infrequent, nonperiodic transitions, the voltage potential between  $V_{SS}$  and the  $V_{CC}$  may undershoot to -2.0V for periods less than 20ns, or overshoot to  $V_{CC,max} + 2.0V$  for periods less than 20ns.
  3. JEDEC Standard JESD22-A114A ( $C1 = 100pF$ ,  $R1 = 1500\Omega$ ,  $R2 = 500\Omega$ ).

**Table 44: Operating Conditions**

Symbol	Parameter	Min	Max	Units
$V_{CC}$	Supply voltage	1.7	2.0	V
$T_A$	Ambient operating temperature	-40	85	°C

**Table 45: Input/Output Capacitance**

Note 1 applies to entire table

Symbol	Description	Test Condition	Min	Max	Units
$C_{IN/OUT}$	Input/output capacitance (DQ0/DQ1/DQ2/DQ3)	$V_{OUT} = 0V$	–	8	pF
$C_{IN}$	Input capacitance (other pins)	$V_{IN} = 0V$	–	6	pF

Note: 1. These parameters are sampled only, not 100% tested.  $T_A = 25^\circ C$  at 54 MHz.



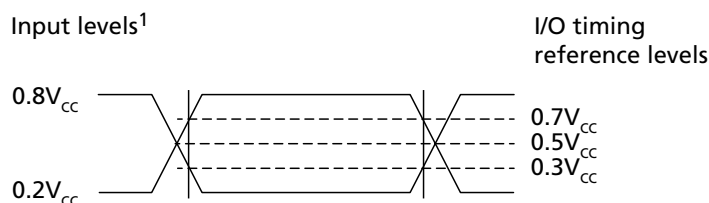
## 512Mb, 1.8V Multiple I/O Serial Flash Memory Absolute Ratings and Operating Conditions

**Table 46: AC Timing Input/Output Conditions**

Symbol	Description	Min	Max	Units	Notes
$C_L$	Load capacitance	10	30	pF	1
–	Input rise and fall times	–	1.5	ns	
	Input pulse voltages	$0.2V_{CC}$ to $0.8V_{CC}$		V	2
	Input timing reference voltages	$0.3V_{CC}$ to $0.7V_{CC}$		V	
	Output timing reference voltages	$V_{CC}/2$	$V_{CC}/2$	V	

- Notes: 1. Output buffers are configurable by user.  
2. For quad/dual operations: 0V to  $V_{CC}$ .

**Figure 40: AC Timing Input/Output Reference Levels**



- Note: 1.  $0.8V_{CC} = V_{CC}$  for dual/quad operations;  $0.2V_{CC} = 0V$  for dual/quad operations.





## 512Mb, 1.8V Multiple I/O Serial Flash Memory DC Characteristics and Operating Conditions

### DC Characteristics and Operating Conditions

**Table 47: DC Current Characteristics and Operating Conditions**

Notes 1–6 apply to entire table

Parameter	Symbol	Test Conditions	Typ	Max	Unit
Input leakage current	$I_{LI}$		–	$\pm 2$	$\mu A$
Output leakage current	$I_{LO}$		–	$\pm 2$	$\mu A$
Standby current	$I_{CC1}$	$S = V_{CC}$ , $V_{IN} = V_{SS}$ or $V_{CC}$	60	100	$\mu A$
Deep power-down current	$I_{CC2}$	$S = V_{CC}$ , $V_{IN} = V_{SS}$ or $V_{CC}$	5	30	$\mu A$
Operating current (fast-read extended I/O)	$I_{CC3}$	$C = 0.1V_{CC}/0.9V_{CC}$ at 133 MHz, DQ1 = open	–	16	mA
		$C = 0.1V_{CC}/0.9V_{CC}$ at 54 MHz, DQ1 = open	–	6	mA
		$C = 0.1V_{CC}/0.9V_{CC}$ at 133 MHz	–	20	mA
		$C = 0.1V_{CC}/0.9V_{CC}$ at 133 MHz	–	22	mA
Operating current (fast-read dual I/O)					
Operating current (fast-read quad I/O)					
Operating current (PROGRAM operations)	$I_{CC4}$	$S\# = V_{CC}$	–	60	mA
Operating current (WRITE operations)	$I_{CC5}$	$S\# = V_{CC}$	–	60	mA
Operating current (erase)	$I_{CC6}$	$S\# = V_{CC}$	–	50	mA

**Table 48: DC Voltage Characteristics and Operating Conditions**

Notes 1–6 apply to entire table

Parameter	Symbol	Conditions	Min	Max	Unit
Input low voltage	$V_{IL}$		–0.5	$0.3V_{CC}$	V
Input high voltage	$V_{IH}$		$0.7V_{CC}$	$V_{CC} + 0.4$	V
Output low voltage	$V_{OL}$	$I_{OL} = 1.6mA$	–	0.4	V
Output high voltage	$V_{OH}$	$I_{OH} = -100\mu A$	$V_{CC} - 0.2$	–	V

- Notes:
1. All currents are RMS unless noted. Typical values at typical  $V_{CC}$  (3.0/1.8V);  $V_{IO} = 0V/V_{CC}$ ;  $T_C = +25^\circ C$ .
  2. Standby current is the average current measured over any time interval 5 $\mu s$  after S de-assertion (and any internal operations are complete).
  3. Deep power-down current is the average current measured 5ms over any 5ms time interval, 100 $\mu s$  after the ENTER DEEP POWER-DOWN operation (and any internal operations are complete).
  4. All read currents are the average current measured over any 1KB continuous read. No load, checker-board pattern.
  5. All program currents are the average current measured over any 256-byte typical data program.
  6.  $V_{IL}$  can undershoot to –1.0V for periods <2ns and  $V_{IH}$  may overshoot to  $V_{CC,max} + 1.0V$  for periods less than 2ns.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory AC Characteristics and Operating Conditions

### AC Characteristics and Operating Conditions

**Table 49: AC Characteristics and Operating Conditions**

Parameter	Symbol	Data Transfer Rate	Min	Typ	Max	Unit	Notes
Clock frequency for all commands other than READ (Extended-SPI, DIO-SPI, and QIO-SPI protocol)	$f_C$	STR	DC	–	133	MHz	
		DTR	DC	–	66		
Clock frequency for READ commands	$f_R$	STR	DC	–	54	MHz	
		DTR	DC	–	27		
Clock HIGH time	$t_{CH}$	STR	3.375	–	–	ns	2
		DTR	6.75	–	–		
Clock LOW time	$t_{CL}$	STR	3.375	–	–	ns	2
		DTR	6.75	–	–		
Clock rise time (peak-to-peak)	$t_{CLCH}$	STR/DTR	0.1	–	–	V/ns	3, 4
Clock fall time (peak-to-peak)	$t_{CHCL}$	STR/DTR	0.1	–	–	V/ns	3, 4
S# active setup time (relative to clock)	$t_{SLCH}$	STR/DTR	3.375	–	–	ns	
S# not active hold time (relative to clock)	$t_{CHSL}$	STR/DTR	3.375	–	–	ns	
Data in setup time	$t_{DVCH}$	STR/DTR	1.75	–	–	ns	
	$t_{DVCL}$	DTR only	1.75	–	–	ns	
Data in hold time	$t_{CHDX}$	STR/DTR	2.5	–	–	ns	
	$t_{CLDX}$	DTR only	2.5	–	–	ns	
S# active hold time (relative to clock)	$t_{CHSH}$	STR	3.375	–	–	ns	
		DTR	6.75	–	–		
S# active hold time (relative to clock LOW) Only for writes in DTR	$t_{CLSH}$	DTR only	3.375	–	–	ns	
S# not active setup time (relative to clock)	$t_{SHCH}$	STR	3.375	–	–	ns	
		DTR	6.75	–	–	ns	
S# deselect time after a READ command	$t_{SHSL1}$	STR/DTR	20	–	–	ns	
S# deselect time after a nonREAD command	$t_{SHSL2}$	STR/DTR	50	–	–	ns	
Output disable time	$t_{SHQZ}$	STR/DTR	–	–	7	ns	3
Clock LOW to output valid under 30pF	$t_{CLQV}$	STR/DTR	–	–	6	ns	
Clock LOW to output valid under 10pF		STR/DTR	–	–	5	ns	
Clock HIGH to output valid under 30pF	$t_{CHQV}$	DTR only	–	–	6	ns	
Clock HIGH to output valid under 10pF		DTR only	–	–	5	ns	
Output hold time	$t_{CLQX}$	STR/DTR	1	–	–	ns	
Output hold time	$t_{CHQX}$	DTR only	1	–	–	ns	
HOLD setup time (relative to clock)	$t_{HLCH}$	STR/DTR	3.375	–	–	ns	
HOLD hold time (relative to clock)	$t_{CHHH}$	STR/DTR	3.375	–	–	ns	
HOLD setup time (relative to clock)	$t_{HHCH}$	STR/DTR	3.375	–	–	ns	



## 512Mb, 1.8V Multiple I/O Serial Flash Memory AC Characteristics and Operating Conditions

**Table 49: AC Characteristics and Operating Conditions (Continued)**

Parameter	Symbol	Data Transfer Rate	Min	Typ	Max	Unit	Notes
HOLD hold time (relative to clock)	$t_{CHHL}$	STR/DTR	3.375	–	–	ns	
HOLD to output Low-Z	$t_{HHQX}$	STR/DTR	–	–	8	ns	3
HOLD to output High-Z	$t_{HLQZ}$	STR/DTR	–	–	8	ns	3
Write protect setup time	$t_{WHSL}$	STR/DTR	20	–	–	ns	5
Write protect hold time	$t_{SHWL}$	STR/DTR	100	–	–	ns	5
S# HIGH to deep power-down	$t_{DP}$	STR/DTR	3	–	–	us	
S# HIGH to standby mode (DPD exit time)	$t_{RDP}$	STR/DTR	30	–	–	us	
WRITE STATUS REGISTER cycle time	$t_W$	STR/DTR	–	1.3	8	ms	
WRITE NONVOLATILE CONFIGURATION REGISTER cycle time	$t_{WNVCR}$	STR/DTR	–	0.2	1	s	
Nonvolatile sector lock time	$t_{PPBP}$	STR/DTR	–	0.1	2.8	ms	
Program ASP register	$t_{ASPP}$	STR/DTR	–	0.1	0.5	ms	
Program password	$t_{PASSP}$	STR/DTR	–	0.2	0.8	ms	
Erase nonvolatile sector lock array	$t_{PPBE}$	STR/DTR	–	0.2	1	s	
Page program time (256 bytes)	$t_{PP}$	STR/DTR	–	200	2800	us	
PROGRAM OTP cycle time (64 bytes)	$t_{POTP}$	STR/DTR	–	0.12	0.8	ms	
Sector erase time	$t_{SE}$	STR/DTR	–	0.15	1	s	
4KB subsector erase time	$t_{SSE}$	STR/DTR	–	0.05	0.4	s	
32KB subsector erase time	$t_{SSE}$	STR/DTR	–	0.1	1	s	
512Mb bulk erase time	$t_{BE}$	STR/DTR	–	153	460	s	

- Notes:
1. Typical values given for  $T_A = 25\text{ }^{\circ}\text{C}$ .
  2.  $t_{CH} + t_{CL}$  must add up to  $1/f_C$ .
  3. Value guaranteed by characterization; not 100% tested.
  4. Expressed as a slew-rate.
  5. Only applicable as a constraint for a WRITE STATUS REGISTER command when STATUS REGISTER WRITE is set to 1.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory AC Reset Specifications

### AC Reset Specifications

**Table 50: AC RESET Conditions**

Note 1 applies to entire table

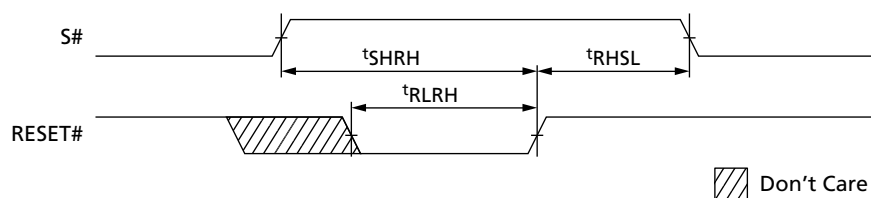
Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Reset pulse width	$t_{RLRH}^2$		50	—	—	ns
Reset recovery time	$t_{RHSL}$	Device deselected (S# HIGH) and is in XIP mode	40	—	—	ns
		Device deselected (S# HIGH) and is in standby mode	40	—	—	ns
		Commands are being decoded, any READ operations are in progress or any WRITE operation to volatile registers are in progress	40	—	—	ns
		Any device array PROGRAM/ERASE/SUSPEND/RESUME, PROGRAM OTP, NONVOLATILE SECTOR LOCK, and ERASE NONVOLATILE SECTOR LOCK ARRAY operations are in progress	30	—	—	$\mu$ s
		While a WRITE STATUS REGISTER operation is in progress	—	$t_W$	—	ms
		While a WRITE NONVOLATILE CONFIGURATION REGISTER operation is in progress	—	$t_{WNVCR}$	—	ms
		On completion or suspension of a SUBSECTOR ERASE operation	—	$t_{SSE}$	—	s
		Device in deep power-down mode	—	$t_{RDP}$	—	ms
		While ADVANCED SECTOR PROTECTION PROGRAM operation is in progress	—	$t_{ASPP}$	—	ms
		While PASSWORD PROTECTION PROGRAM operation is in progress	—	$t_{PASSP}$	—	ms
Software reset recovery time	$t_{SHSL3}$	Device deselected (S# HIGH) and is in standby mode	40	—	—	ns
		Any Flash array PROGRAM/ERASE/SUSPEND/RESUME, PROGRAM OTP, NONVOLATILE SECTOR LOCK, and ERASE NONVOLATILE SECTOR LOCK ARRAY operations are in progress	30	—	—	$\mu$ s
		While WRITE STATUS REGISTER operation is in progress	—	$t_W$	—	ms
		While a WRITE NONVOLATILE CONFIGURATION REGISTER operation is in progress	—	$t_{WNVCR}$	—	ms
		On completion or suspension of a SUBSECTOR ERASE operation	—	$t_{SSE}$	—	s
		Device in deep power-down mode	—	$t_{RDP}$	—	ms
		While ADVANCED SECTOR PROTECTION PROGRAM operation is in progress	—	$t_{ASPP}$	—	ms
		While PASSWORD PROTECTION PROGRAM operation is in progress	—	$t_{PASSP}$	—	ms
S# deselect to reset valid	$t_{SHRV}$	Deselect to reset valid in quad output or in QIO-SPI	—	—	2	ns

- Notes:
1. Values are guaranteed by characterization; not 100% tested.
  2. The device reset is possible but not guaranteed if  $t_{RLRH} < 50$ ns.

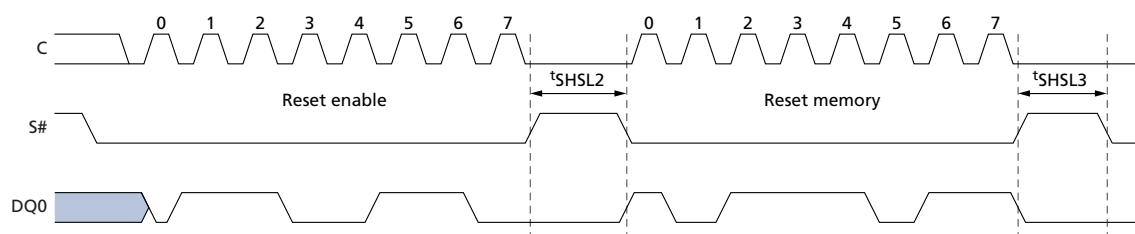


## 512Mb, 1.8V Multiple I/O Serial Flash Memory AC Reset Specifications

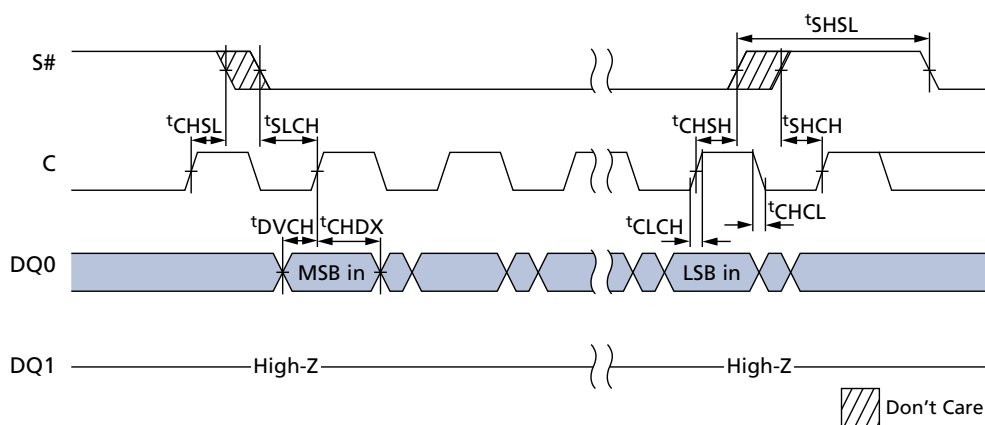
**Figure 41: Reset AC Timing During PROGRAM or ERASE Cycle**



**Figure 42: Reset Enable**



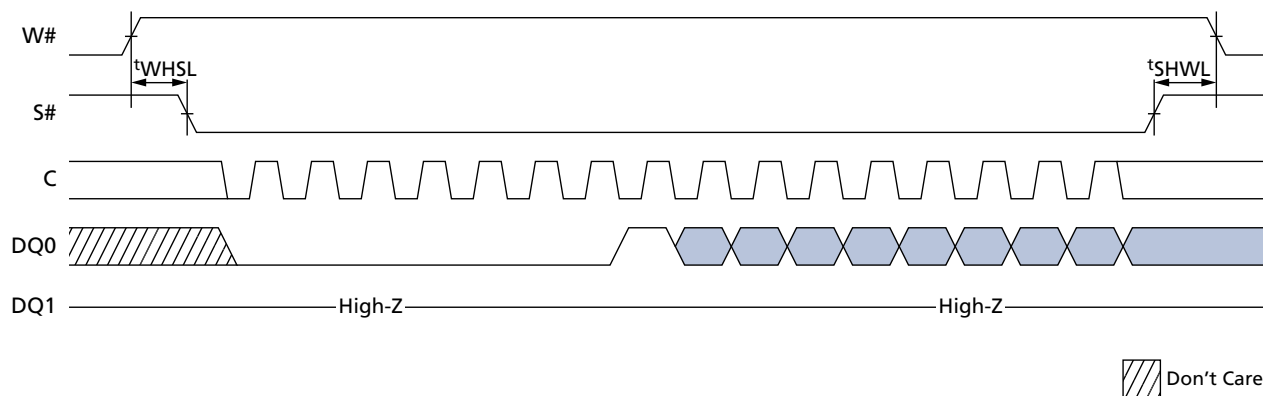
**Figure 43: Serial Input Timing**





## 512Mb, 1.8V Multiple I/O Serial Flash Memory AC Reset Specifications

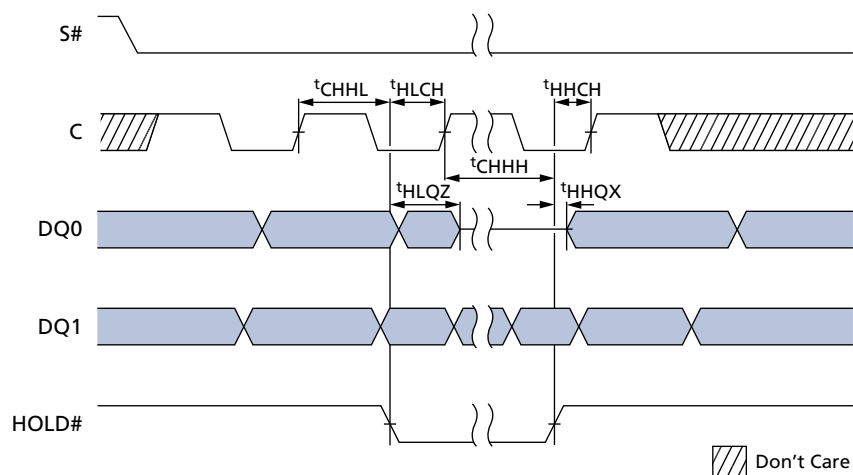
**Figure 44: Write Protect Setup and Hold During WRITE STATUS REGISTER Operation (SRWD = 1)**



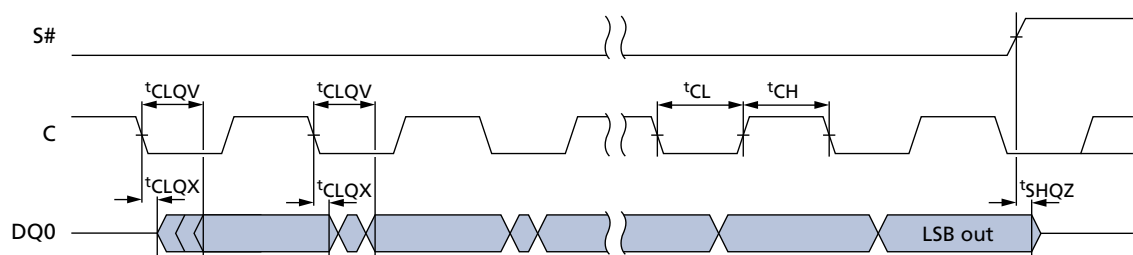


## 512Mb, 1.8V Multiple I/O Serial Flash Memory AC Reset Specifications

**Figure 45: Hold Timing**



**Figure 46: Output Timing**





## 512Mb, 1.8V Multiple I/O Serial Flash Memory Program/Erase Specifications

### Program/Erase Specifications

**Table 51: Program/Erase Specifications**

Parameter	Condition	Typ	Max	Units	Notes
Erase to suspend	Sector erase or erase resume to erase suspend	150	–	μs	1
Program to suspend	Program resume to program suspend	5	–	μs	1
Subsector erase to suspend	Subsector erase or subsector erase resume to erase suspend	50	–	μs	1
Suspend latency	Program	7	25	μs	2
Suspend latency	Subsector erase	15	25	μs	2
Suspend latency	Erase	15	25	μs	3

- Notes:
1. Timing is not internally controlled.
  2. Any READ command accepted.
  3. Any command except the following are accepted: SECTOR, SUBSECTOR, or BULK ERASE; WRITE STATUS REGISTER; WRITE NONVOLATILE CONFIGURATION REGISTER; and PROGRAM OTP.

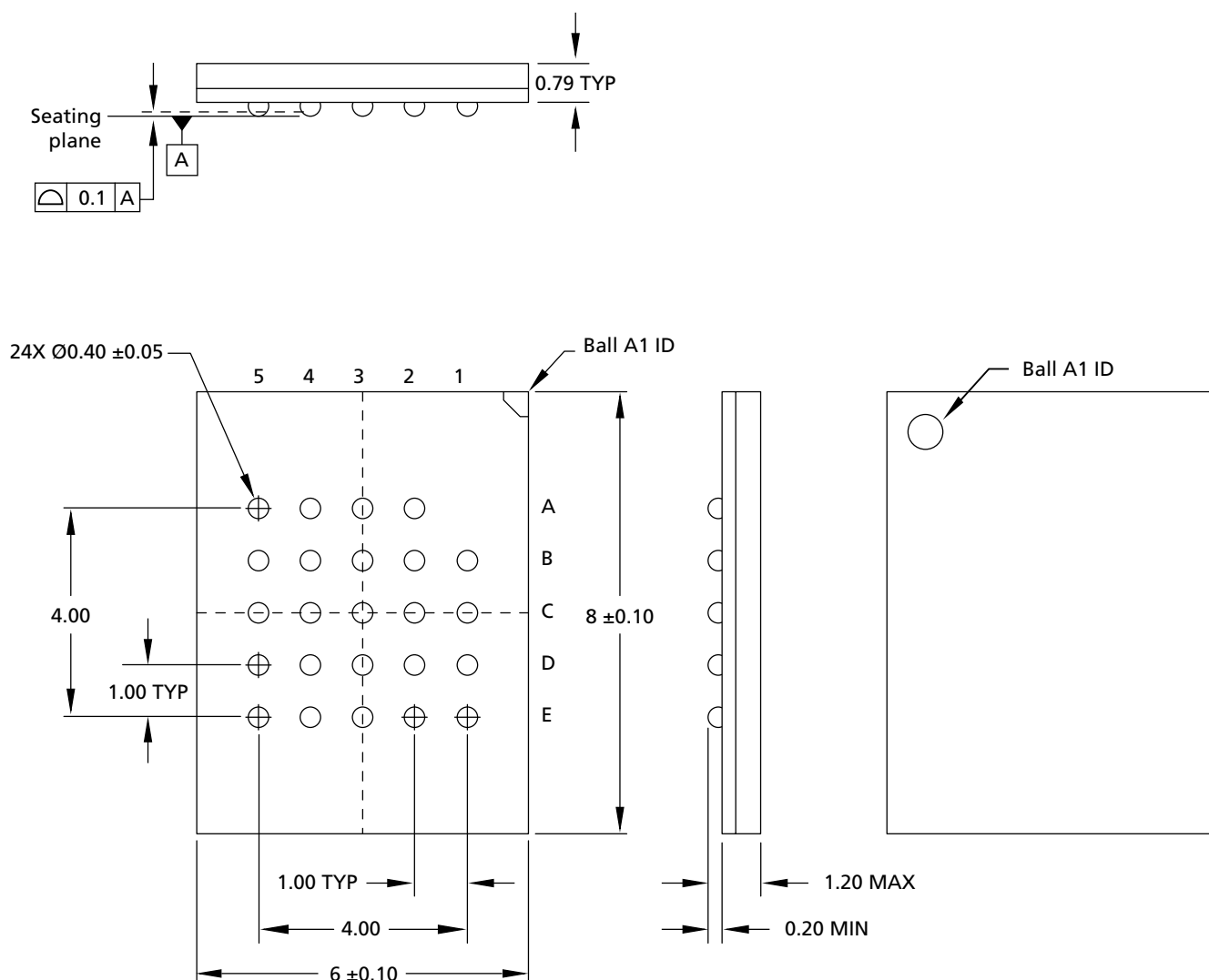




## 512Mb, 1.8V Multiple I/O Serial Flash Memory Package Dimensions – 24-Ball T-PBGA

### Package Dimensions – 24-Ball T-PBGA

Figure 47: 5 x 5 ball grid array – 6mm x 8mm (Package Code: 12)



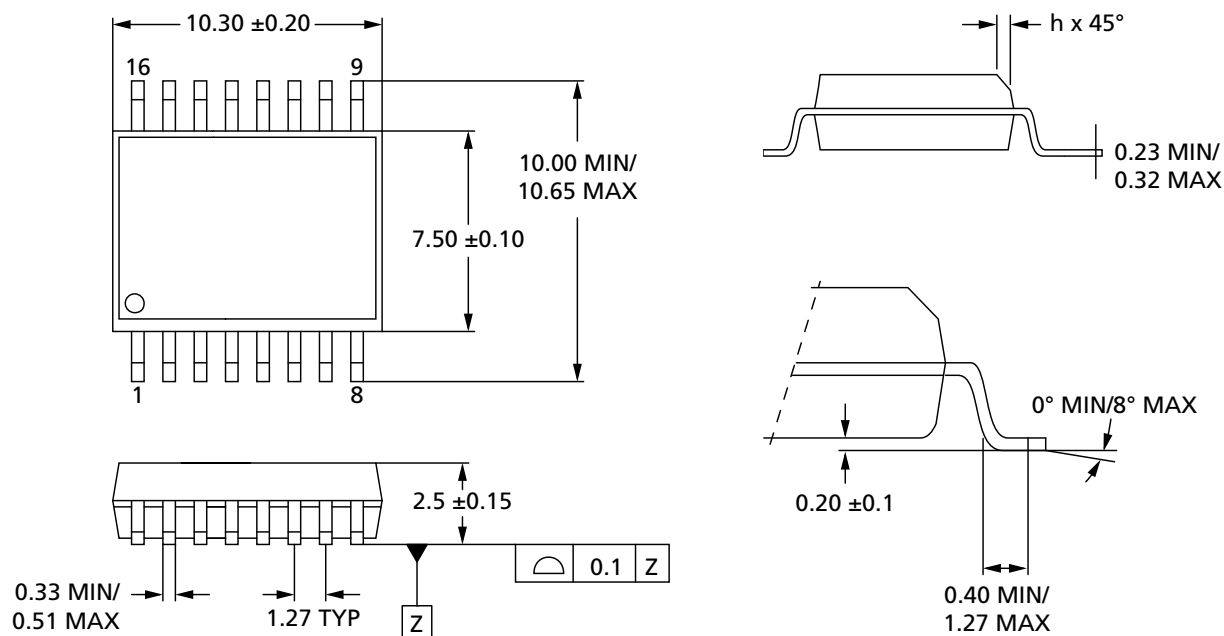
- Notes:
1. All dimensions are in millimeters.
  2. See Part Number Ordering Information for complete package names and details.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Package Dimensions – 16-Pin SOP2

### Package Dimensions – 16-Pin SOP2

Figure 48: 300mm Body Width– Package Code: SF



- Notes:
1. All dimensions are in millimeters.
  2. See Part Number Ordering Information for complete package names and details.



## 512Mb, 1.8V Multiple I/O Serial Flash Memory Revision History

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### Revision History

#### Rev. A – 012/13

- Preliminary status initial release

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This data sheet contains initial characterization limits that are subject to change upon full characterization of production devices.